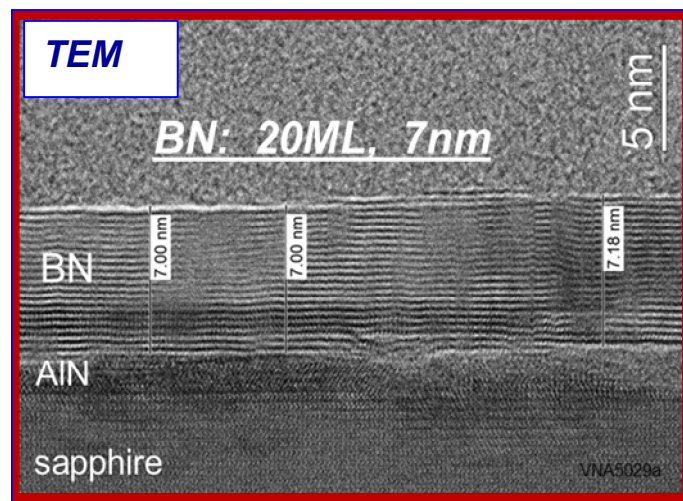
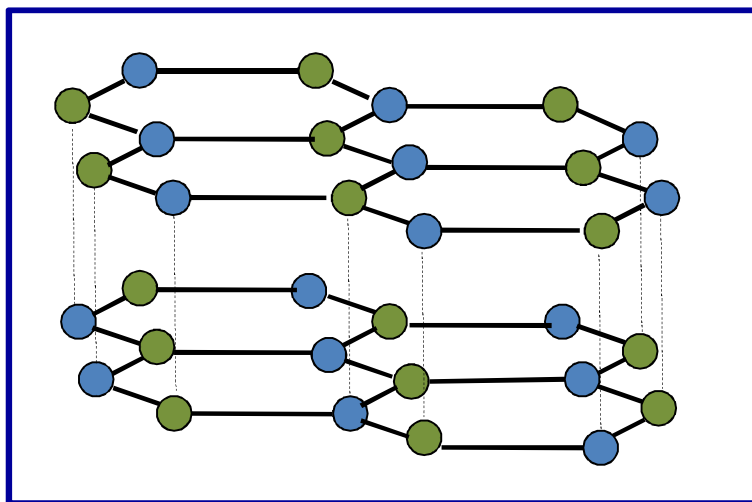


Properties of Hexagonal BN Grown by High-Temperature Metal-organic Vapor Phase Epitaxy

M. Crawford, A. Rice, A. Allerman, T. Beechem, T. Ohta, D. Medlin, C. Spataru, J. Figiel, M. Smith

Sandia National Laboratories, Albuquerque, NM 87185



Sandia National Laboratories is a multi-mission laboratory managed and operated by National Technology and Engineering Solutions of Sandia, LLC., a wholly owned subsidiary of Honeywell International, Inc., for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-NA-0003525.



Outline

1. INTRODUCTION

- a) Background and motivation
- b) Excitonic properties

2. EPITAXIAL GROWTH AND CHARACTERIZATION OF hBN

a) MOVPE Growth at $\leq 1200^{\circ}\text{C}$

- Pulsed growth conditions
- Structural and optical properties

b) MOVPE Growth at $1200 - 1700^{\circ}\text{C}$

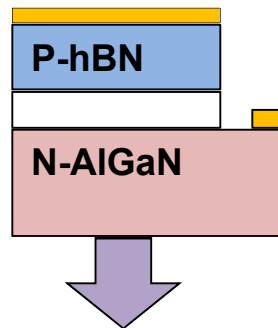
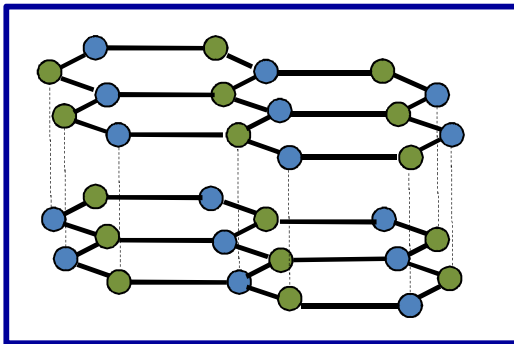
- Excitonic properties vs. growth temperature
- Growth control to the monolayer limit (expt. and model)
- Alternative substrates to sapphire
- Alternative precursors

3. SUMMARY

Background

Motivation

- Ideal template for high-mobility graphene
- Very wide bandgap 2D material (deep UV)
- Demonstrated p-type doping
- $\sim > 10\times$ exciton binding energy of GaN

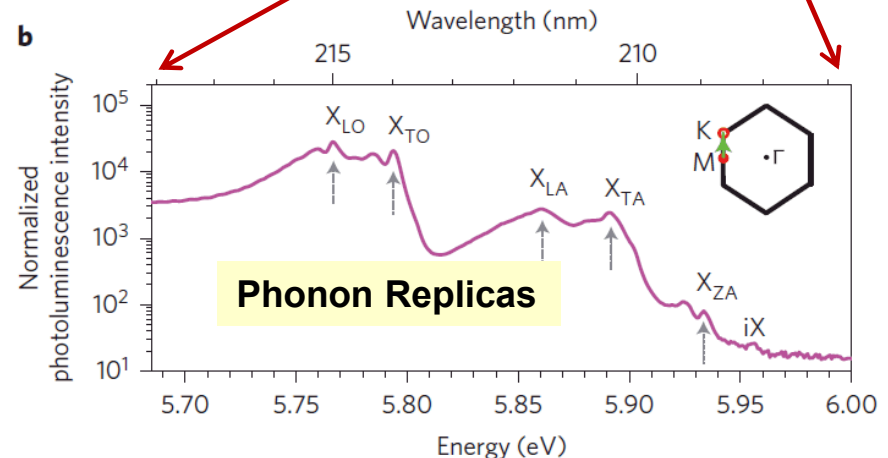
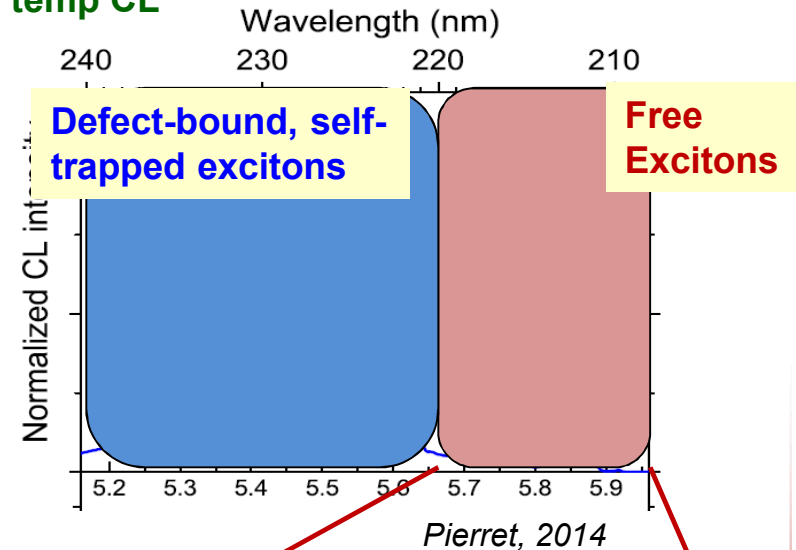


Outstanding Questions for Epitaxy:

- Can we demonstrate large-area hBN with high quality surfaces for 2D heterostructures?
- Can we demonstrate ML to few-ML thickness control?
- Can we observe free-exciton-related emission at room-temperature?

Excitonic Properties

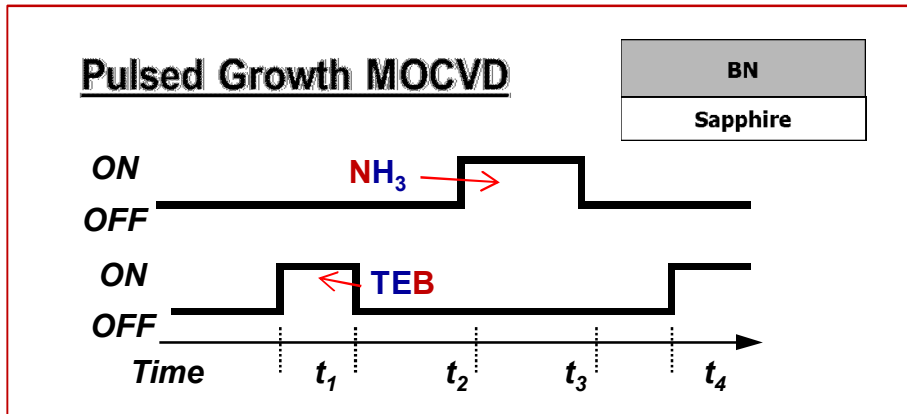
Low temp CL



Cassabois et al., Nat. Photon 2016

MOVPE Growth ($T_g \sim 1175^\circ\text{C}$)

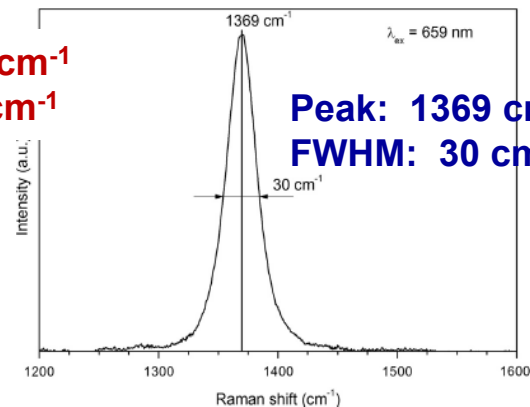
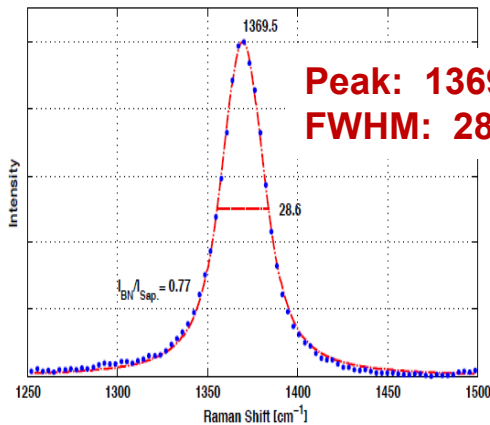
- **Continuous growth:** high growth rate at low V/III but poor crystalline quality
- **Pulsed growth** chosen to enable higher V/III ratios for improved film quality



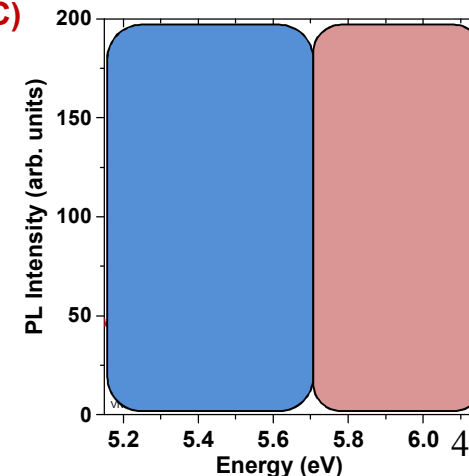
Growth Condition	Parameter Range
Temperature	1175°C
Pressure	50-200 Torr
NH_3 Flow	0.2-10 slm
TEB Flow	3-12 $\mu\text{moles/min}$
Pulse Cycles	20-9600
Time per Cycle	1-12 sec

Raman Spectra

Compare to Chuboruv 2014 (1500°C)

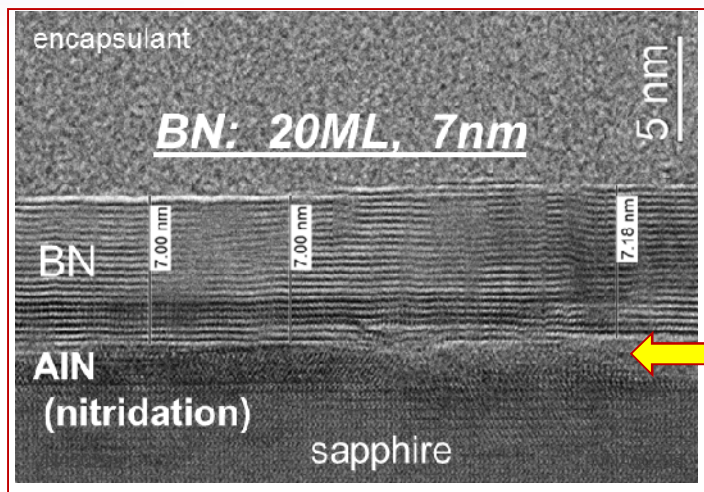


Room Temp PL

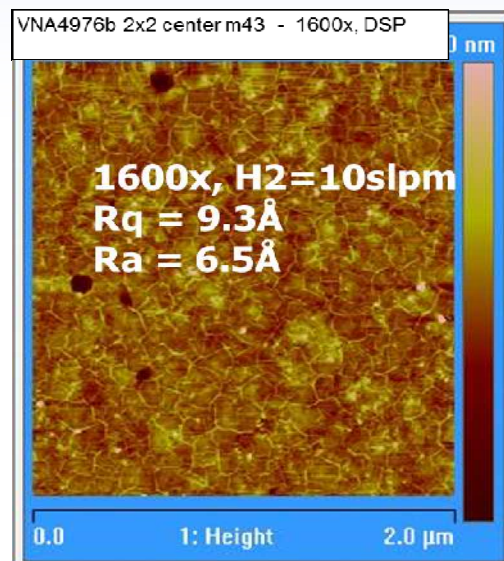


Structure and Morphology of hBN ($T_g \sim 1175^\circ\text{C}$)

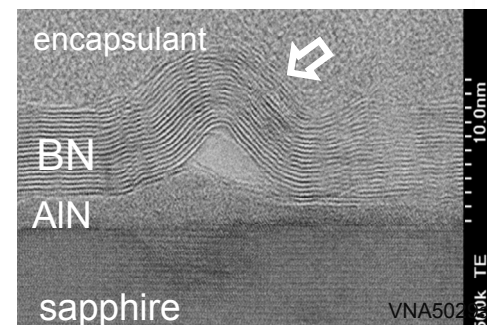
High-resolution cross-section TEM



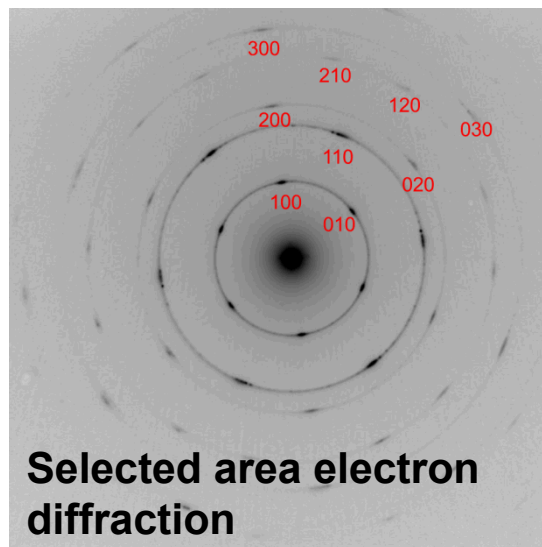
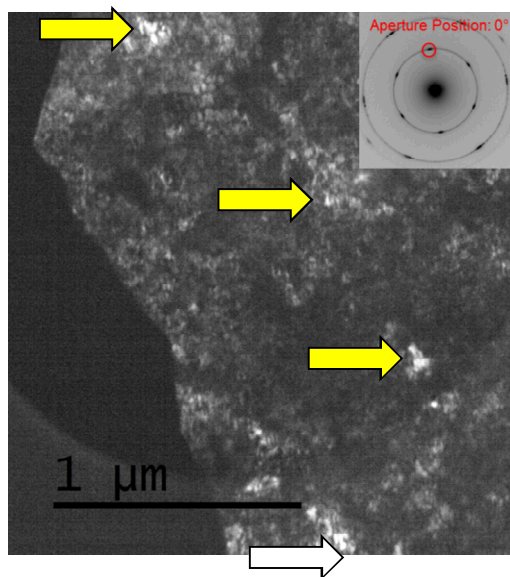
AFM



- Typical “wrinkles”
- Also particles forming on surface with increasing thickness



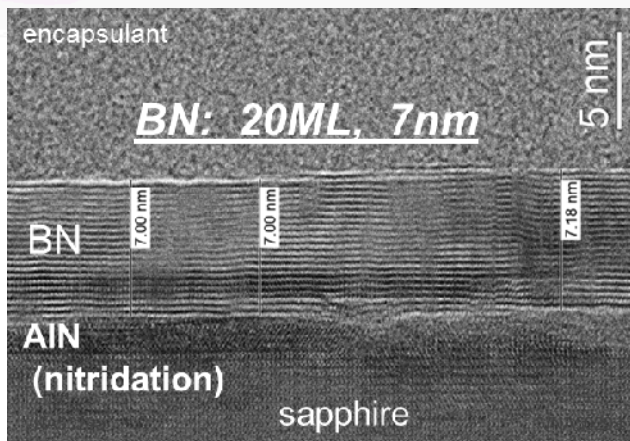
TEM (dark-field) free-standing BN



- Bright regions indicate strong in-plane alignment
- $hk0$ rings indicate in-plane rotation disorder
- $hk0$ reflection spots indicate basal plane alignment

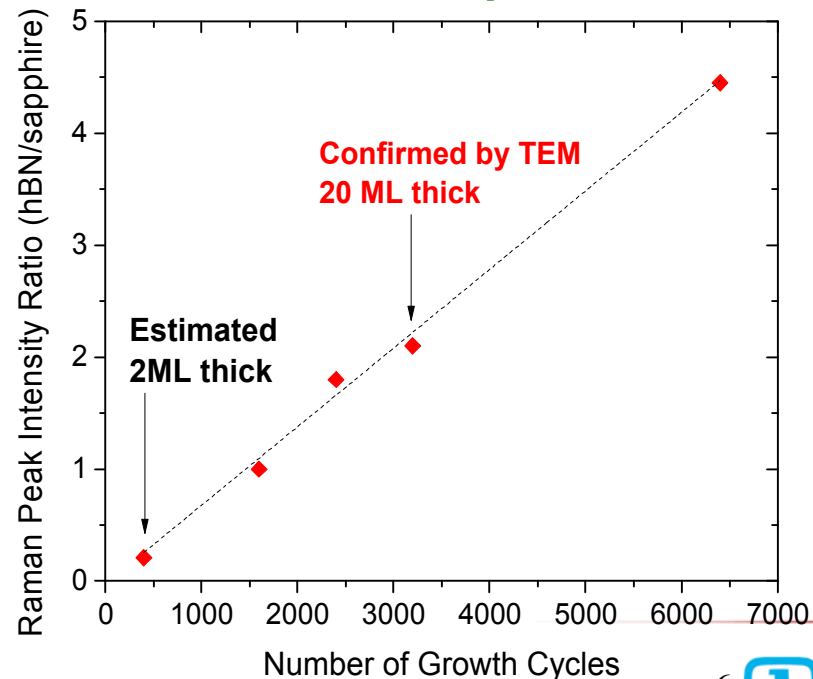
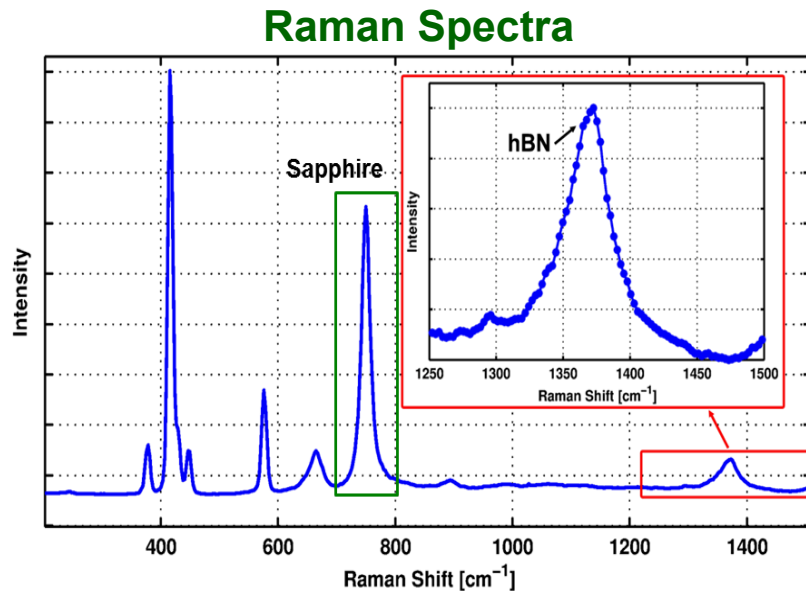
Estimation of Film thicknesses: Raman

Cross-sectional TEM



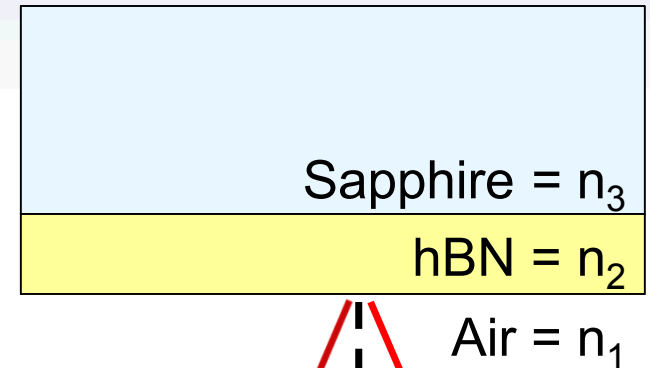
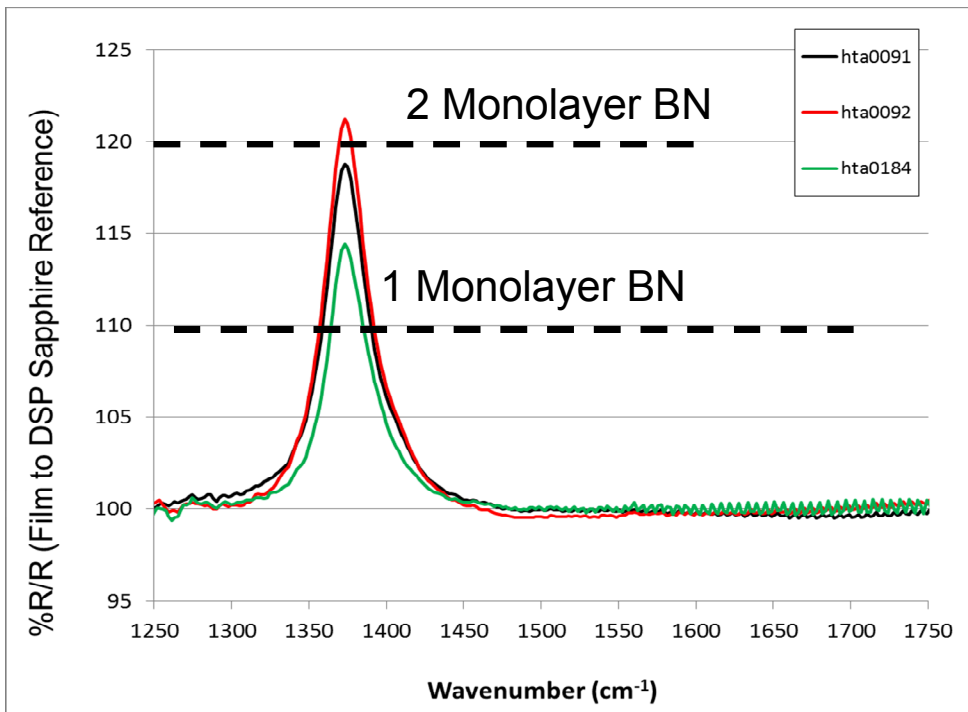
- Difficulty seeing very thin layers by TEM
- Using hBN/sapphire Raman intensity ratio, calibrated to TEM of thicker films, as a rough estimate of thickness
- Suggests reproducible 1-3 ML control

BN Raman peak ratio ($I_{\text{BN}}/I_{\text{sapp}}$) vs. Pulse Cycles



Estimation of Film thicknesses: FTIR

- Take advantage of the large difference between BN and sapphire extinction coefficients
- Apply 3-layer differential reflectance model
- Yields $\Delta R/R \sim 110\%$ for $d = 1$ ML
- Averages for partial coverage



$$\frac{\Delta R}{R} = \frac{8\pi d n_1}{\lambda} \text{Im} \left(\frac{\hat{\epsilon}_2 - \hat{\epsilon}_3}{\epsilon_1 - \hat{\epsilon}_3} \right)$$

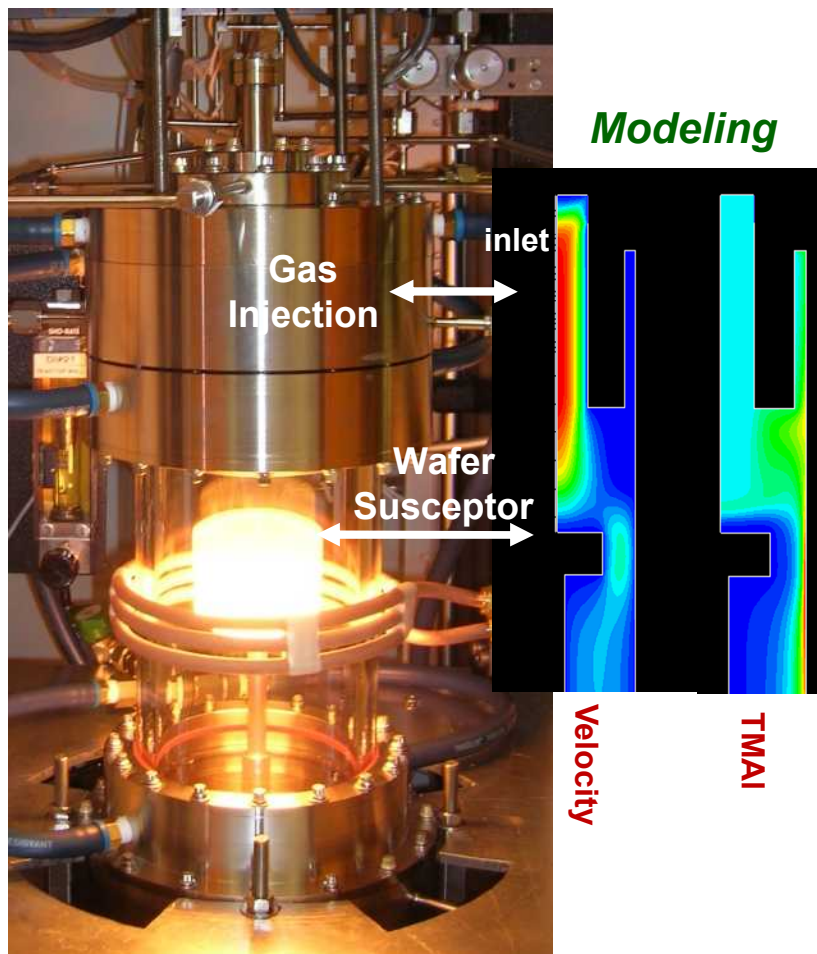
McIntyre and Aspnes., 1971

R. Creighton, SNL

- hBN films between 1 and 2 monolayers by Raman
- Two techniques give similar results, FTIR more consistent

High Temperature MOVPE

>1800°C Operation



- Advantages of HT growth

- Increased surface mobility of Group-III atoms.

- Continuous Growth (TEB + NH₃)

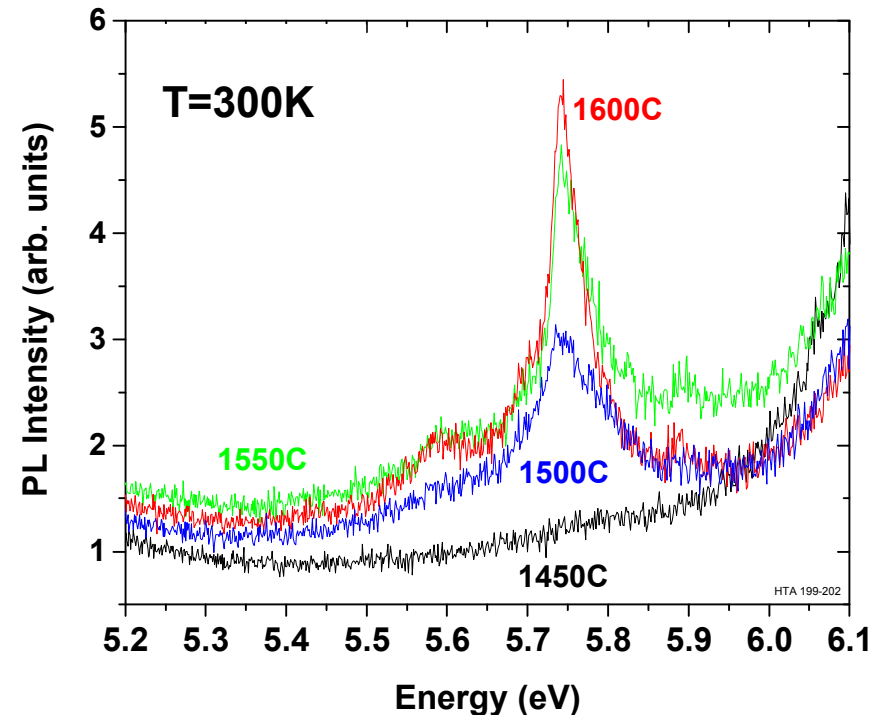
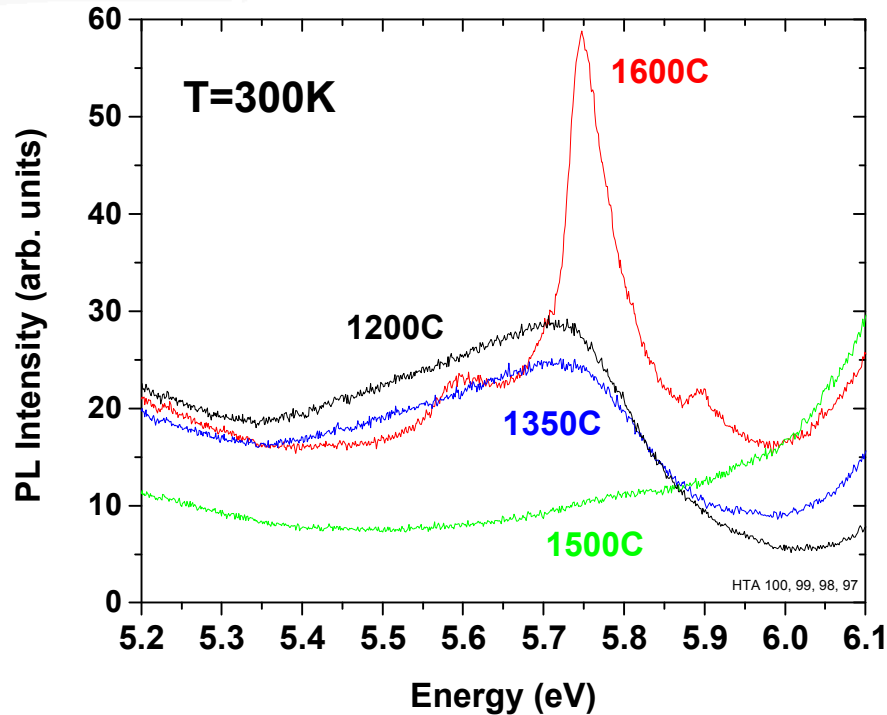
- Temperature: 1200 – 1600 - 1800°C
- Pressure: 50 torr
- NH₃: 0.1 – 2 - 5 slpm
- TEB: 12 μmoles/min
- Carrier gas: N₂
- H₂: 0 – 5 slpm

Reactor Design from Prof. Zlatko Sitar (NC State)

Growth Temperature Study: PL

Wide Temp Range: $T_g = 1200\text{-}1600^\circ\text{C}$

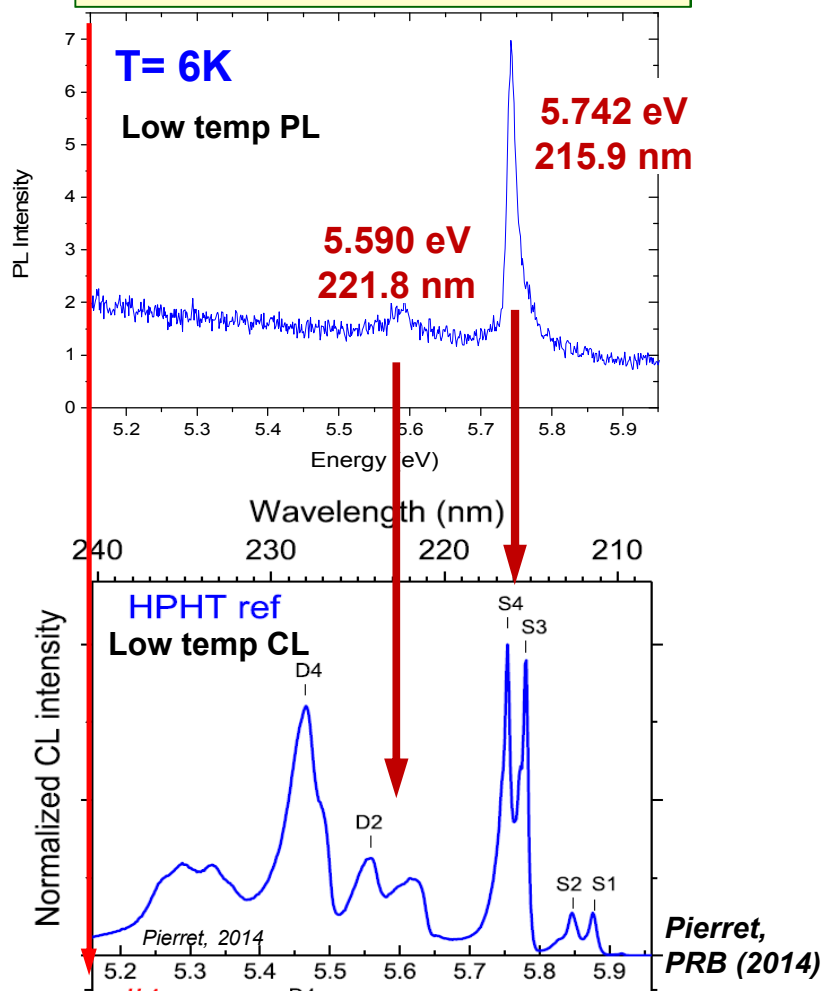
Transition Region: $T_g = 1450\text{-}1600^\circ\text{C}$



- Unusual evolution of near-band-edge features with increasing growth temperature
- Transition to sharp higher-energy free-exciton peak at $T_g \sim 1500\text{-}1600^\circ\text{C}$
- Observation of room temperature free (5.75 eV) exciton in MOVPE hBN

Low-Temperature Luminescence: Comparisons with Bulk and Exfoliated hBN

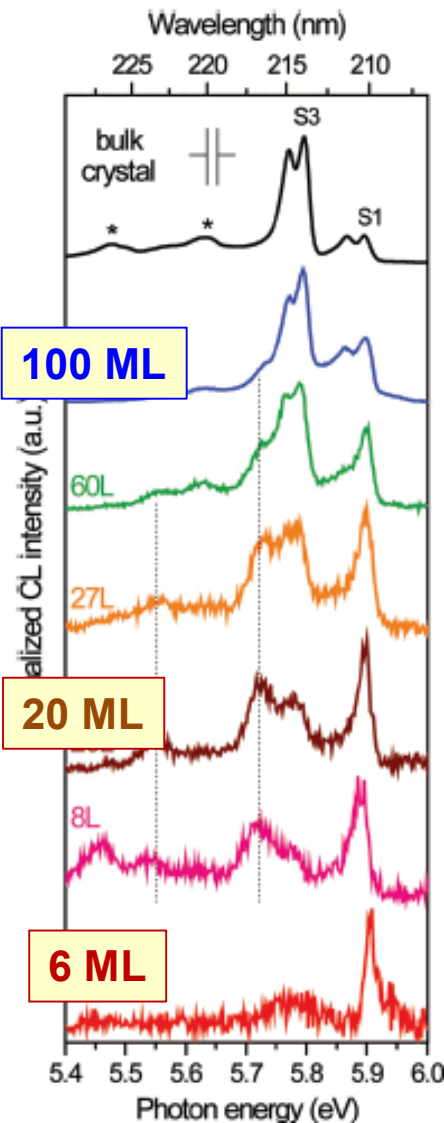
MOVPE hBN: $T_g = 1600^\circ\text{C}$



High-Pressure/High-Temp hBN Crystal

**Exfoliated hBN
Flakes**

Low temp CL
Schue, Nanoscale (2016)



→ Excitonic signatures of few ML MOVPE hBN similar to that of best exfoliated samples from high-quality hBN crystals

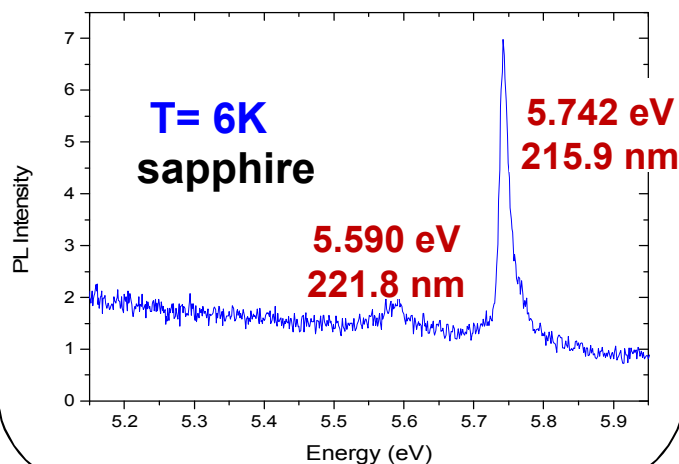
- Evolution to 1 dominant peak (S1) near 5.9 eV with thinner exfoliated layers
- Few-ML MOVPE sample dominated by 5.75 eV peak (S4)

Low-Temperature Luminescence: Comparisons with other Epitaxially-Grown hBN

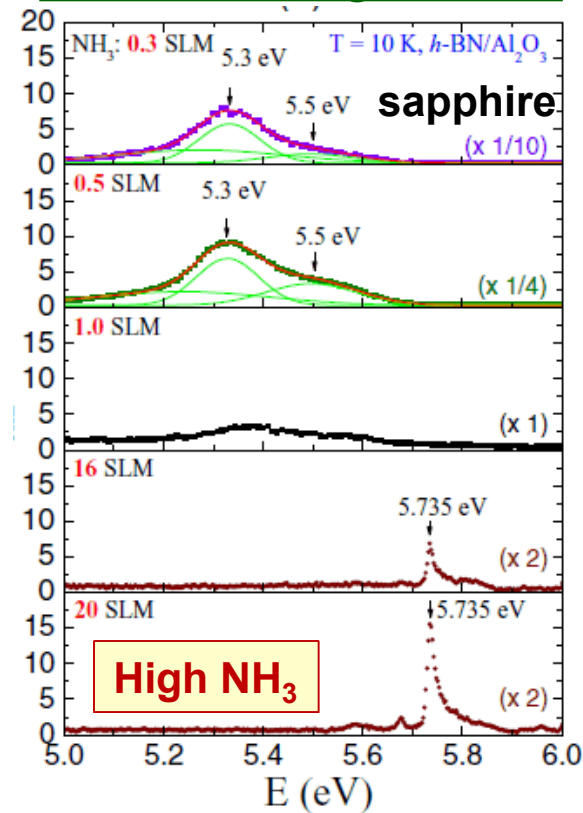
MOVPE: High temp or moderately high temp and high NH_3 yields dominant ~ 5.74 eV peak

MBE: Moderately high temp yields higher energy ~ 5.9 eV peaks on HOPG

MOVPE hBN: $T_g = 1600^\circ\text{C}$



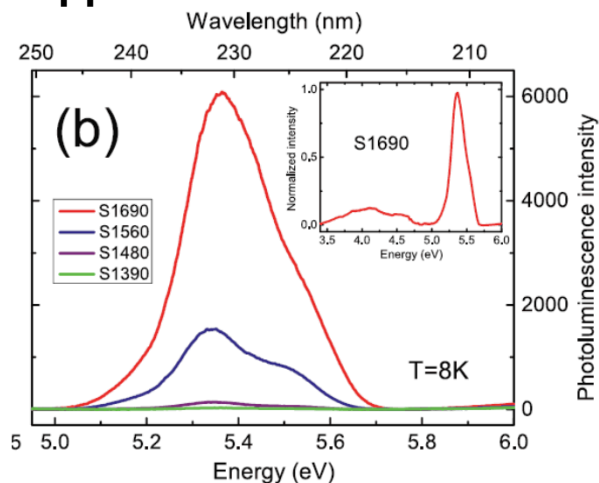
MOVPE hBN: $T_g = 1350^\circ\text{C}$



Du et al., APL (2016)

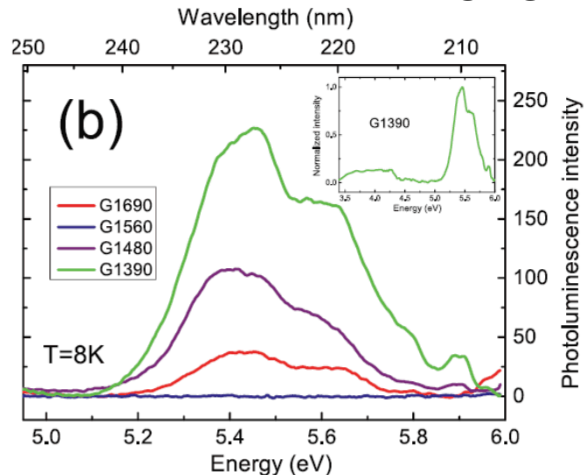
MBE hBN: $T_g = 1390\text{--}1690^\circ\text{C}$

sapphire



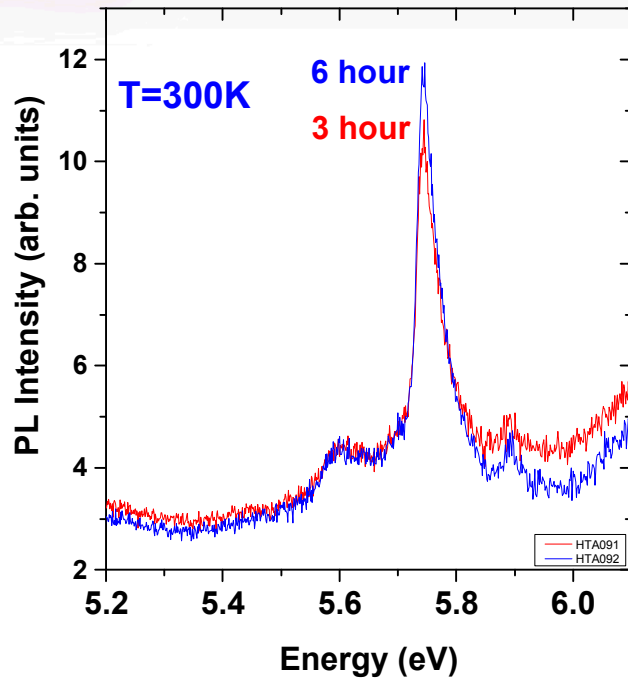
Vuong et al. 2D Mat 2017

HOPG



Potential for Self-limiting Growth at high T_g

PL Measurements



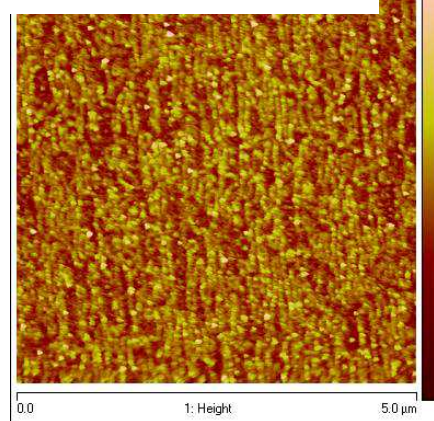
Results from Raman Measurements

Growth Temp (°C)	Growth Time (hrs)	Raman peak ratio	STEM calibration (MLs)
1600	0.25	0.1	~1
1600	3	0.09	~1
1600	3	0.18	~2
1600	6	0.16	~2
1600	24	0.26	~3

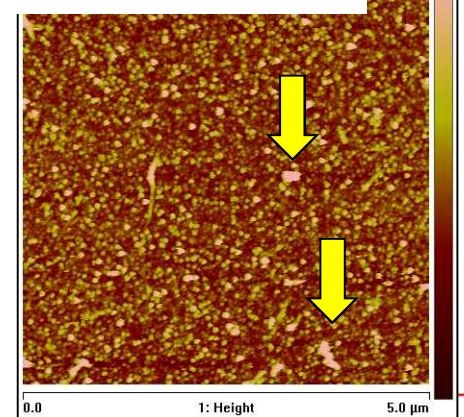
AFM Measurements

- Relatively little change in PL intensity over a large range of growth times
- Raman ratio (hBN/Sapphire) suggests only a few MLs even for 24 hours of growth
- Films roughen, largely due to increased number of larger particulates with longer growth times

0.33 hr 0.971 nm RMS



24 hr 14.1 nm RMS

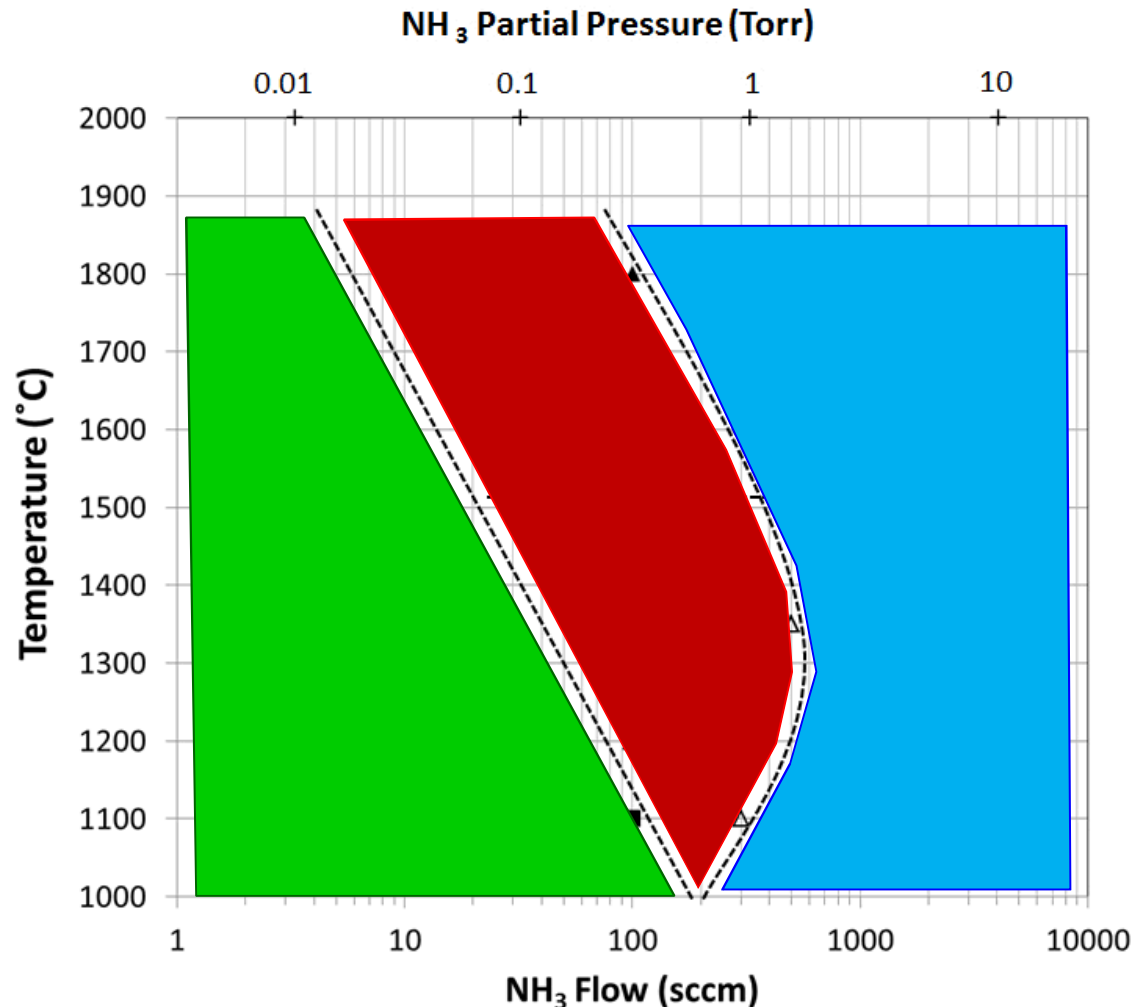


Growth parameter space for achieving few-ML-thick films

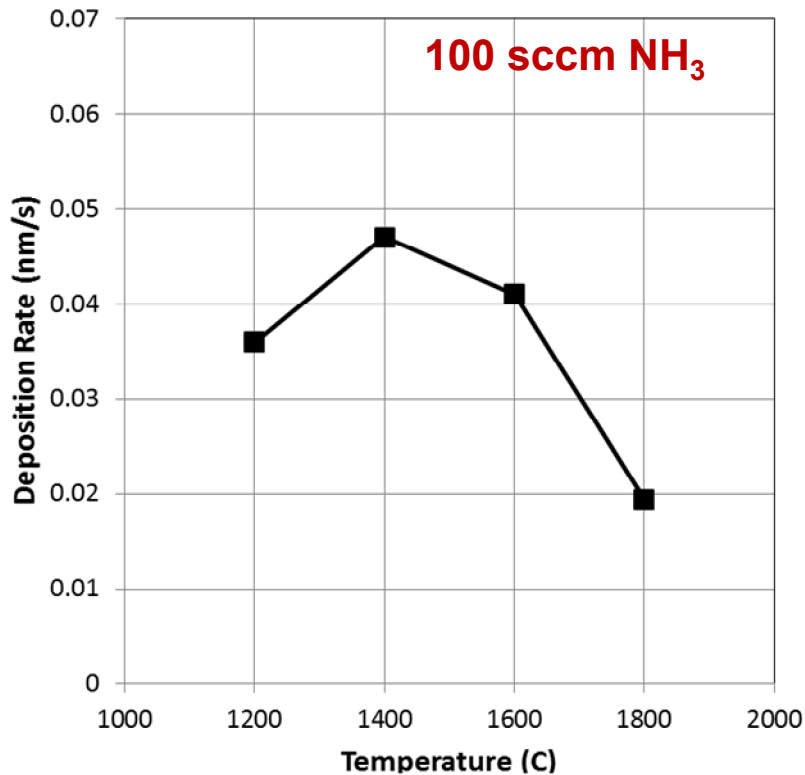
→ Focus on Growth Temperature and NH_3 flow

Growth Regimes

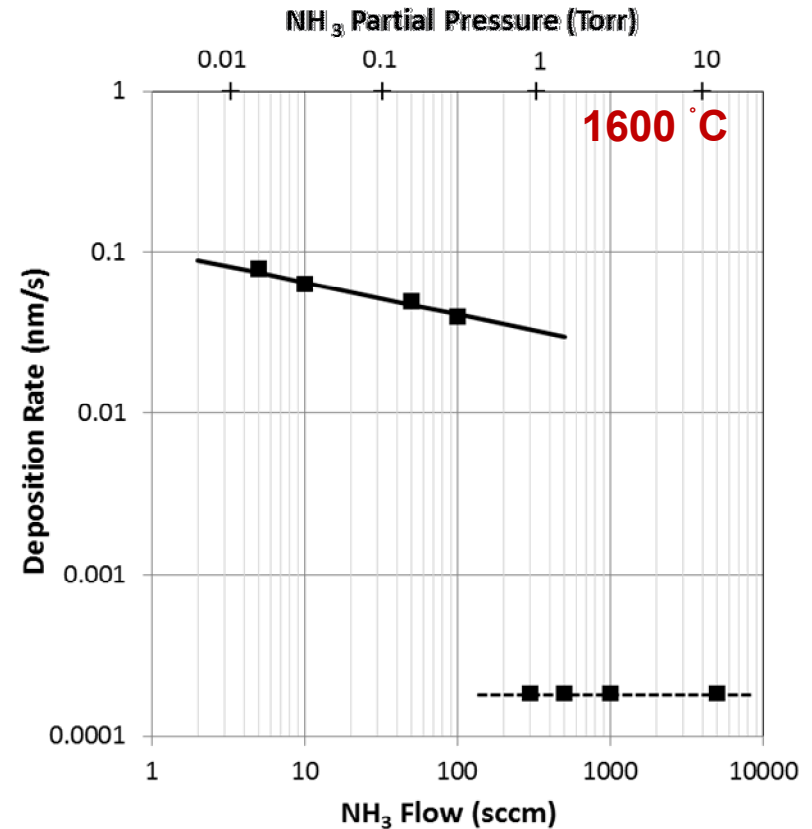
- Low NH_3
 - Thick films
 - Discolored films
- Intermediate NH_3
 - Thick films
 - Clear films
- High NH_3
 - Self-limiting films



Growth rate studies to evaluate self-limiting mechanism



- Growth rate is weakly temperature dependent
- ~2.5x change over 600 °C



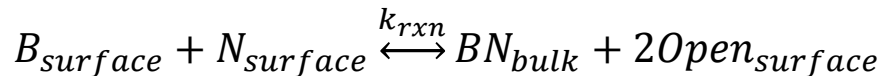
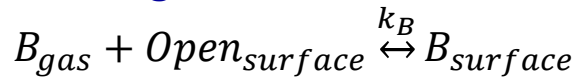
- Critical NH_3 threshold exists for all temperatures
- 2-3 orders of magnitude change in growth rate

→ Trends not consistent with parasitic reactions

Possible Model: Langmuir-Hinshelwood

- Competitive absorption of species that react on a surface

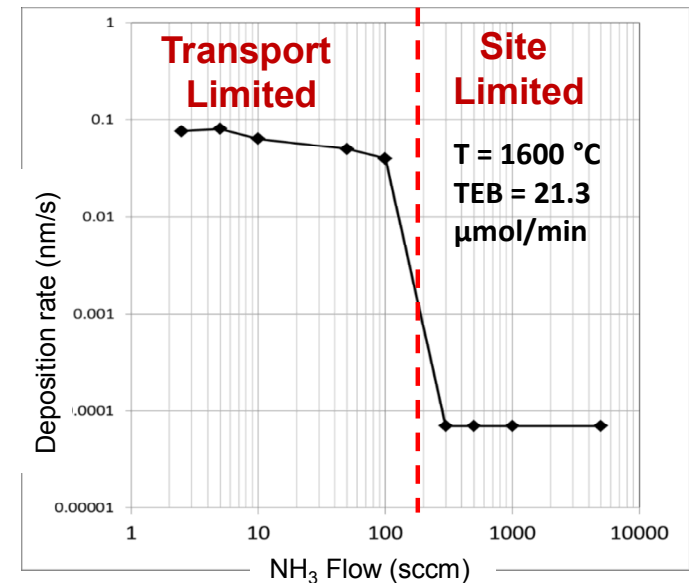
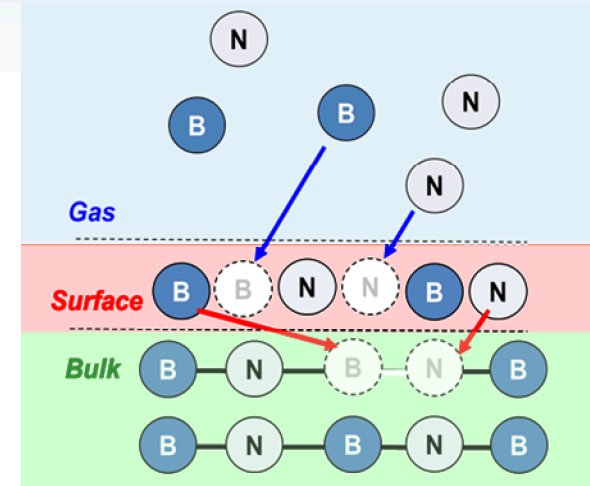
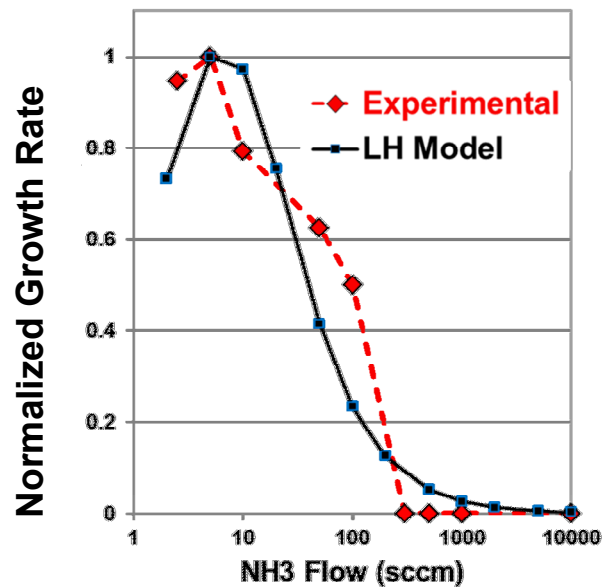
- Controlling reactions:



- Growth rate:

$$G = \frac{k_{rxn} k_B k_N p_B p_N \Gamma^2}{(1 + k_B p_B + k_N p_N)^2}$$

Model captures large decrease in growth rate from microns to monolayers per hour

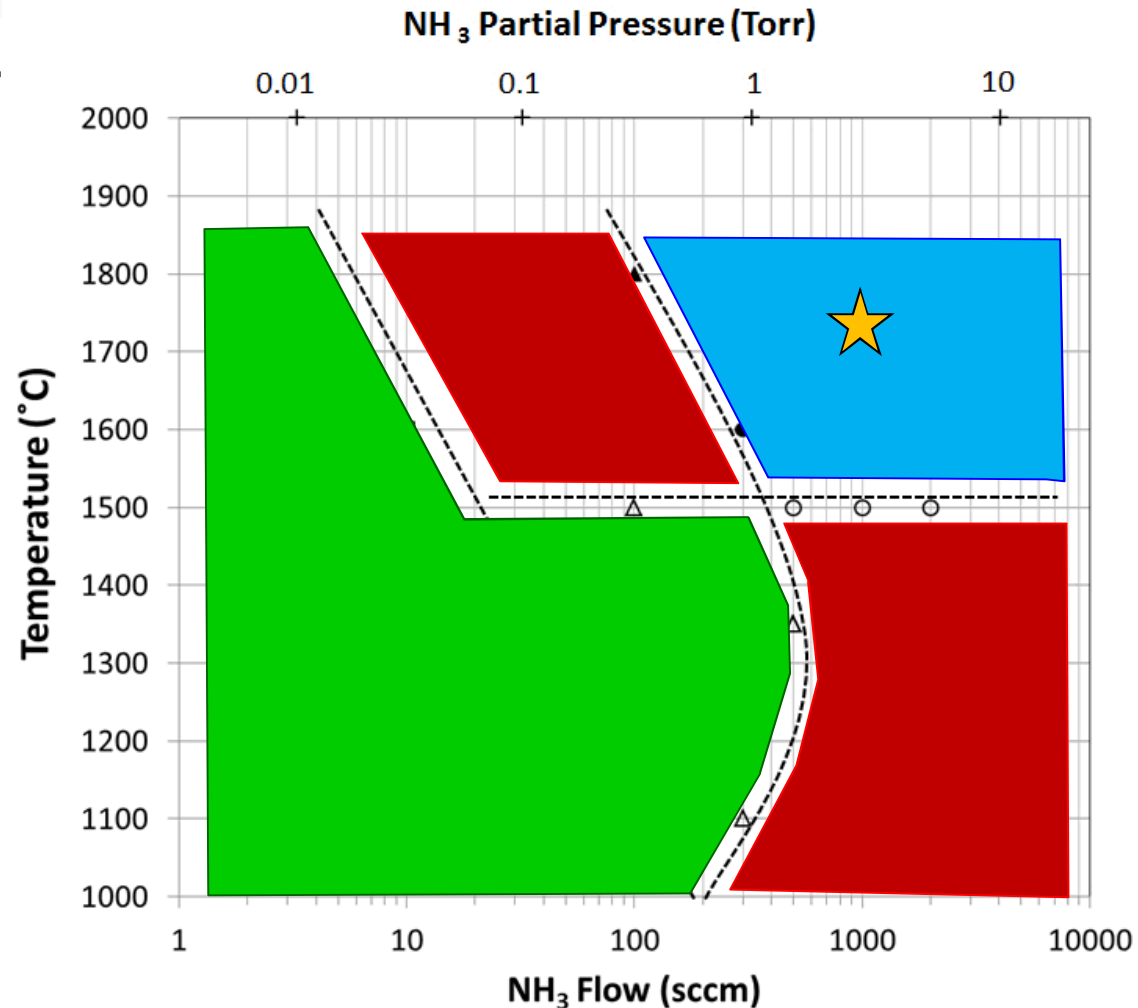


Correlation of Growth Conditions and Excitonic Performance

3 regimes in room temp PL

- No exciton emission
- Defect bound exciton
- Free exciton

RT PL

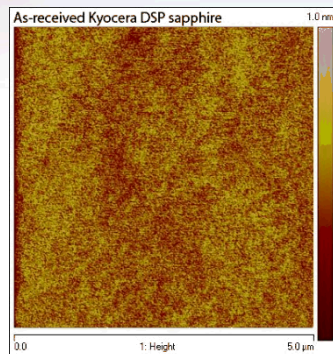


★ High NH₃ and high temperature for RT excitons

Challenge with High Temp Growth: Nitridization of Sapphire Substrate

Sapphire Substrate

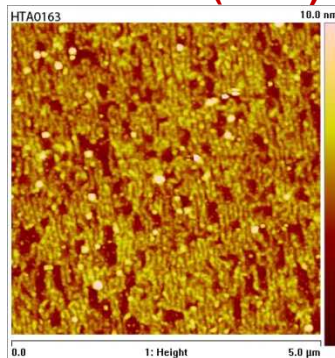
0 min
> 0.1 nm
RMS



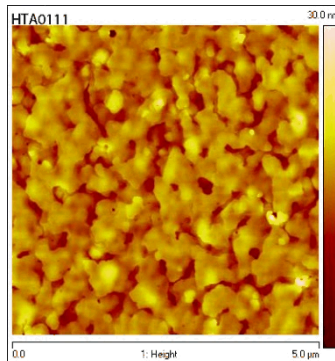
Nitrided Sapphire Substrate

1600°C NH_3 but **No Boron**
Source Material (TEB)

5 min
1.17 nm
RMS

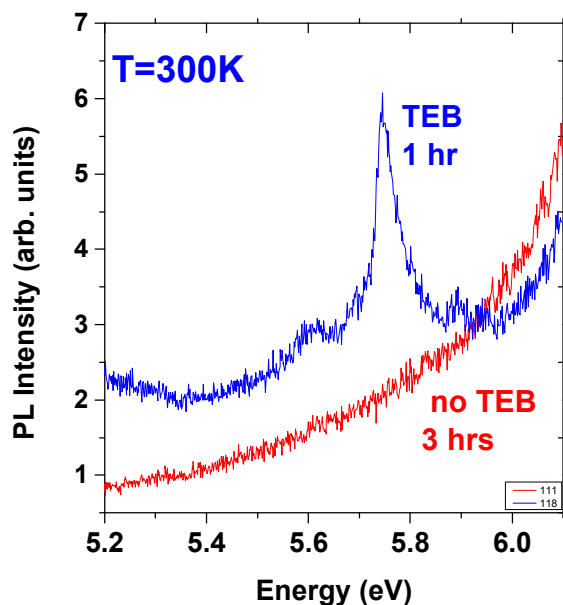


180 min
2.71 nm
RMS

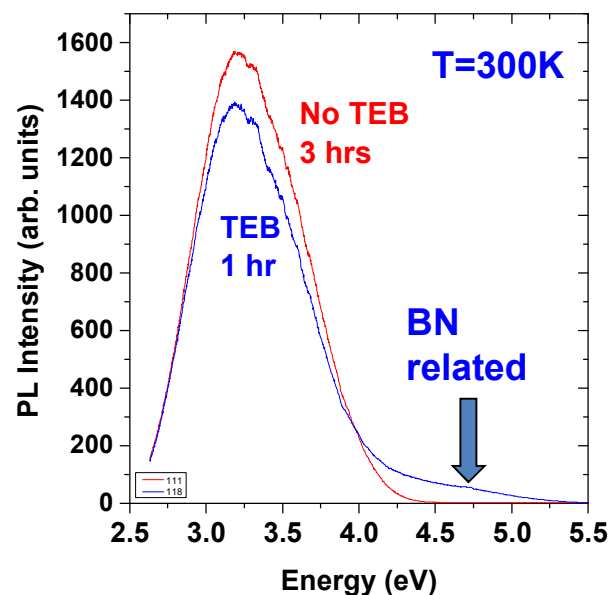


PL comparison: BN on Sapphire vs. Nitrided Sapphire

Near Band Edge



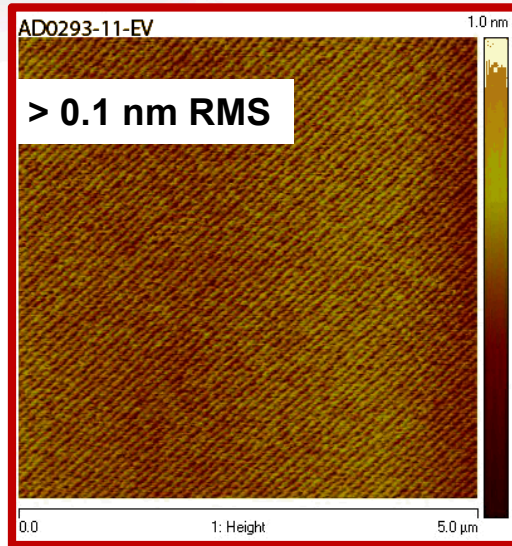
Deep Level



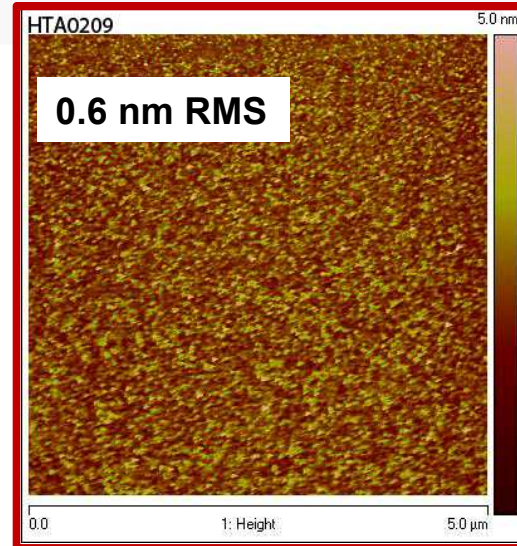
- High temperature NH_3 exposure causes nitridization of sapphire surface (AlN peak seen by Raman)
- Lower crystalline quality than original sapphire, impacts BN morphology
- Contributes strong deep level emission at ~ 3.2 eV

Alternative Substrates: SiC

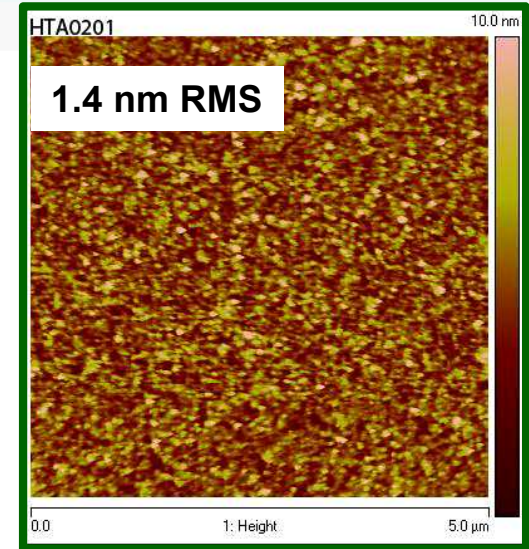
As-received SiC



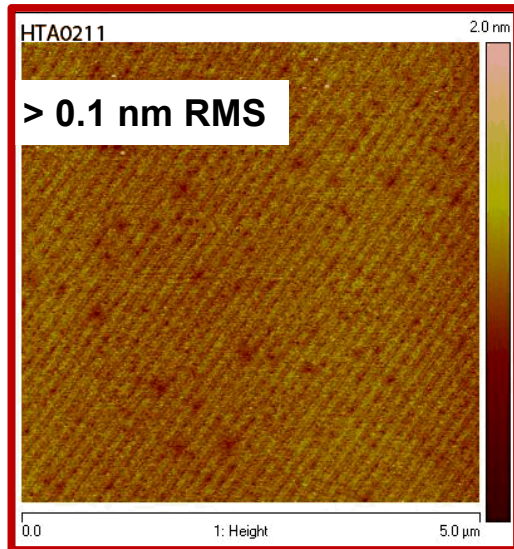
1600°C BN on SiC



1600°C BN on Sapphire



1600°C NH₃ treatment, no TEB



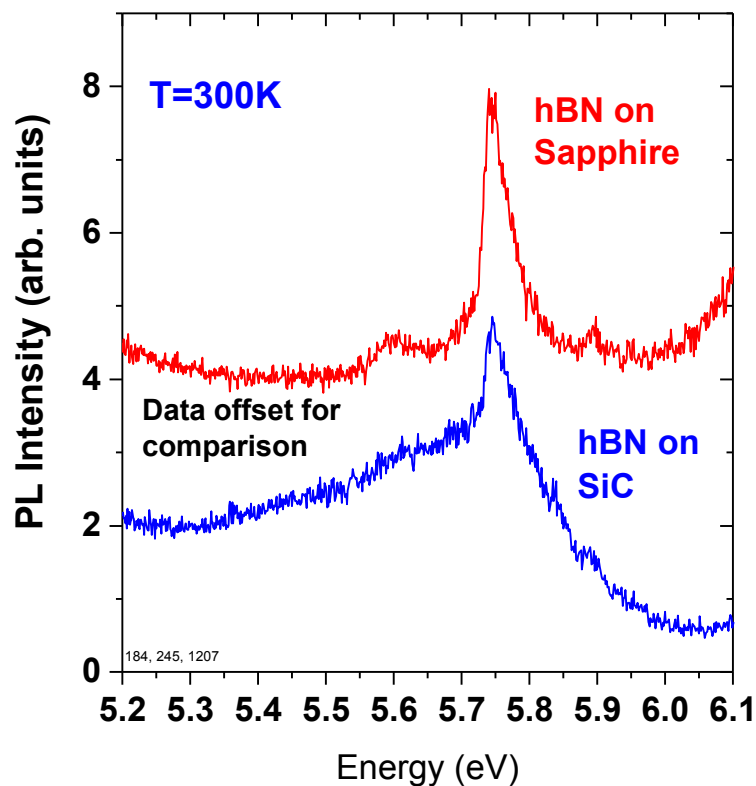
T _g (°C)	RMS roughness (nm)
1400	0.7
1500	0.4
1600	0.6

Growth Conditions: 50 Torr, 25 sccm TEB, 2 SLM NH₃, 1 hour

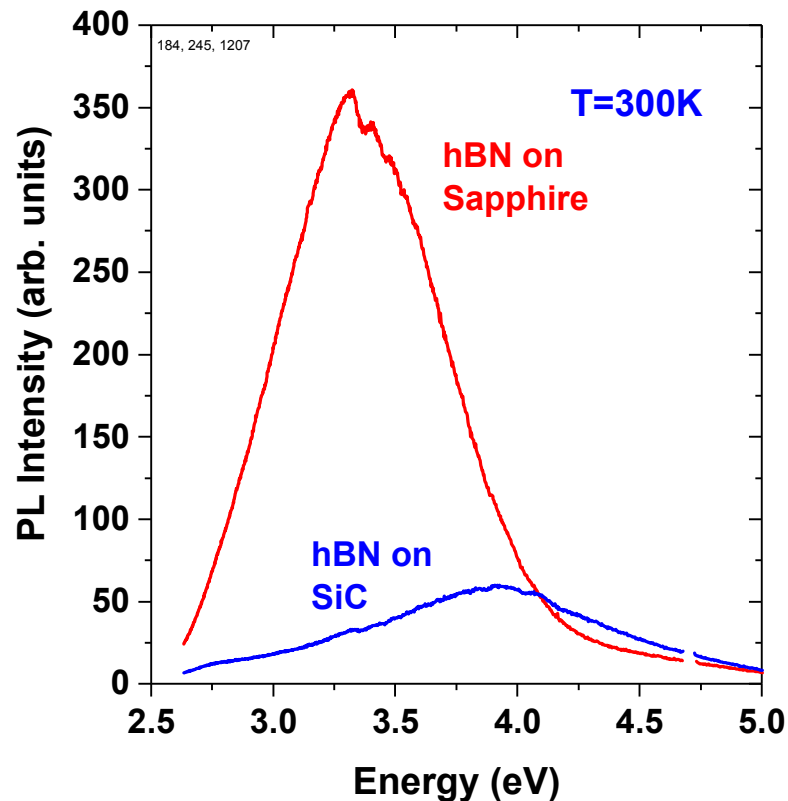
- SiC surface relatively stable with NH₃ exposure
- BN roughness improved over sapphire

hBN on SiC: Luminescence Properties

Near Band Edge PL



Deep Level Emission



- Observe 5.75 eV excitonic peak in room-temp PL, not as well defined as on sapphire
- Elimination of deep level peak associated with nitrated sapphire

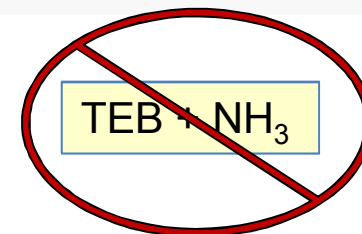
Borazine to reduce sapphire substrate degradation at high temperature

Pros

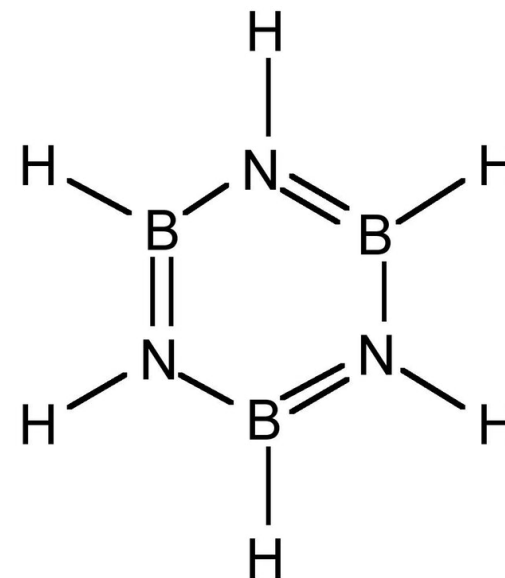
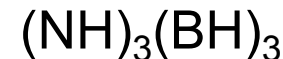
- Literature reports of BN deposition
- High vapor pressure
- Liquid source
- Single source growth

Cons

- Literature reports are mostly on metal
- Stability and purity of source
- Single source growth, e.g., no independent control of V/III ratio

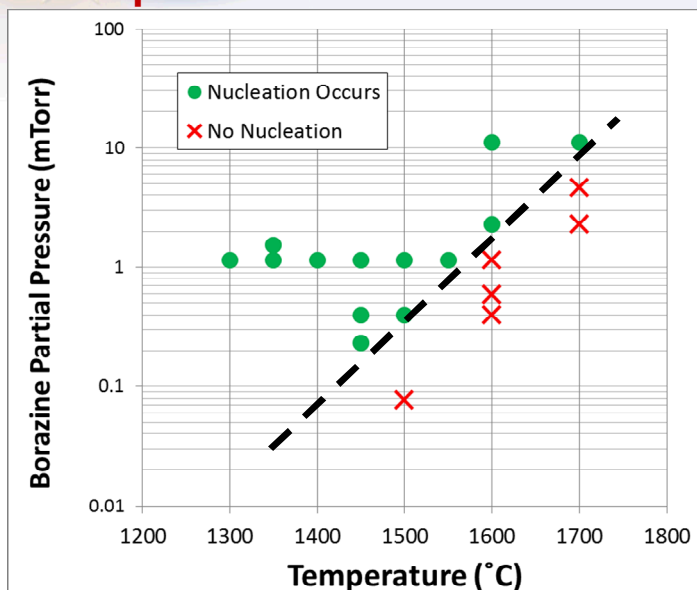


Borazine



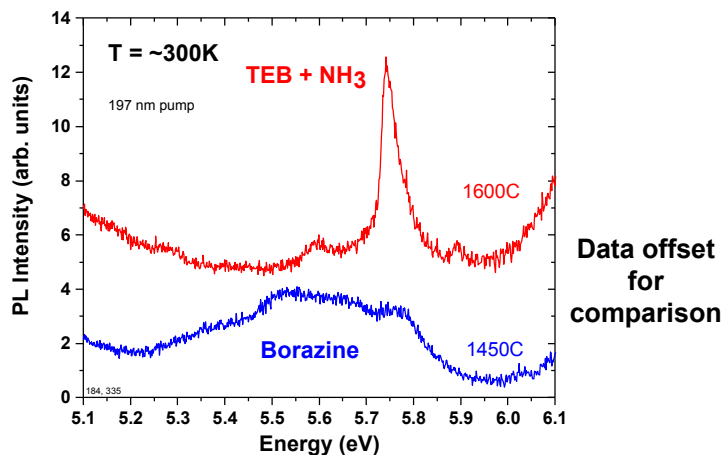
hBN on Sapphire using Borazine

Epitaxial Growth Studies



- Critical borazine partial pressure for nucleation
- Strong function of growth temperature

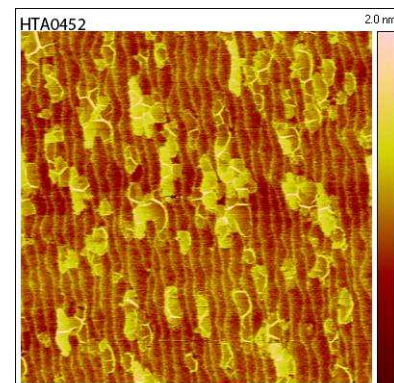
Photoluminescence (~300K)



Characteristic Morphologies (AFM)

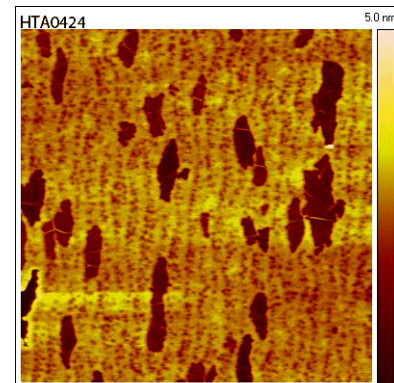
≤ 1 ML

RMS roughness ~0.2 nm



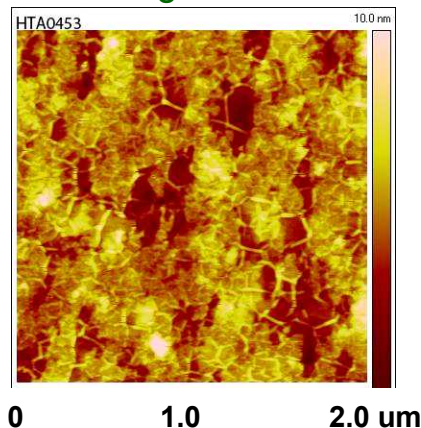
1 - 3 MLs

RMS roughness ~0.5 nm



≥ 3 ML

RMS roughness > 1 nm



- Morphology largely determined by thickness
- Not a strong function of borazine partial pressure or temperature

Summary

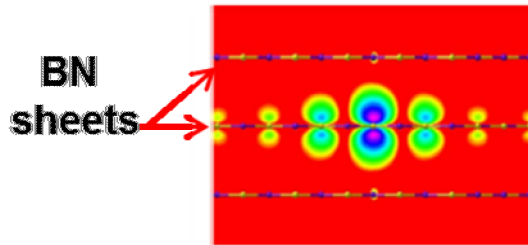
- Explored high- T_g MOVPE as an approach to achieving high-quality, few-ML-thick hBN films
- Lower- T_g films (pulsed growth) demonstrated notable in-plane rotational disorder and defect-related excitonic signatures
- Dramatic evolution of excitonic properties with T_g ; $T_g \sim 1600^\circ\text{C}$ yielded strong free exciton features similar to best exfoliated crystals
- Proposed site-blocking model to explain self-limiting growth of few ML thickness at high- T_g
- SiC substrates or Borazine precursor are promising to avoid sapphire substrate degradation at high temperatures
- Growth of few-ML-thick hBN films on sapphire using Borazine; studied nucleation, structural and optical properties

- Extra Slides

Excitonic Properties at Few-Monolayer Thickness

Question: How do the excitonic properties of hBN evolve with thickness down to 1 ML?

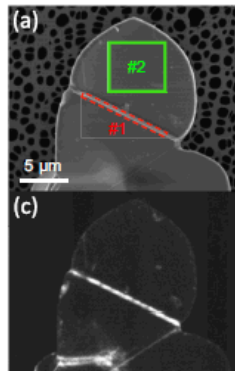
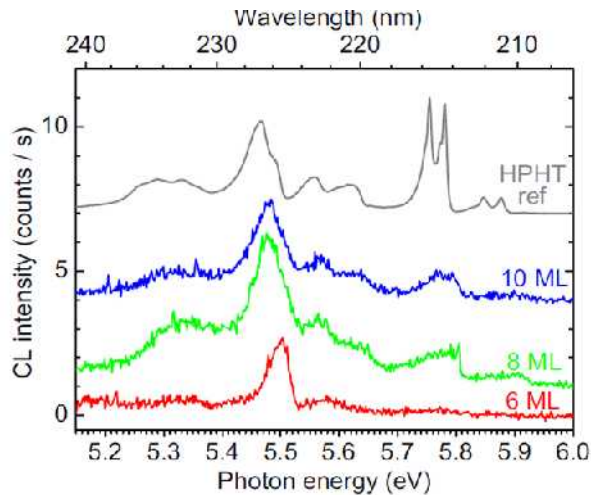
Strong Exciton Confinement



Exciton probability density (5.78 eV)

Arnaud, PRL(2006)

Low Temp. CL: Exfoliated hBN flakes

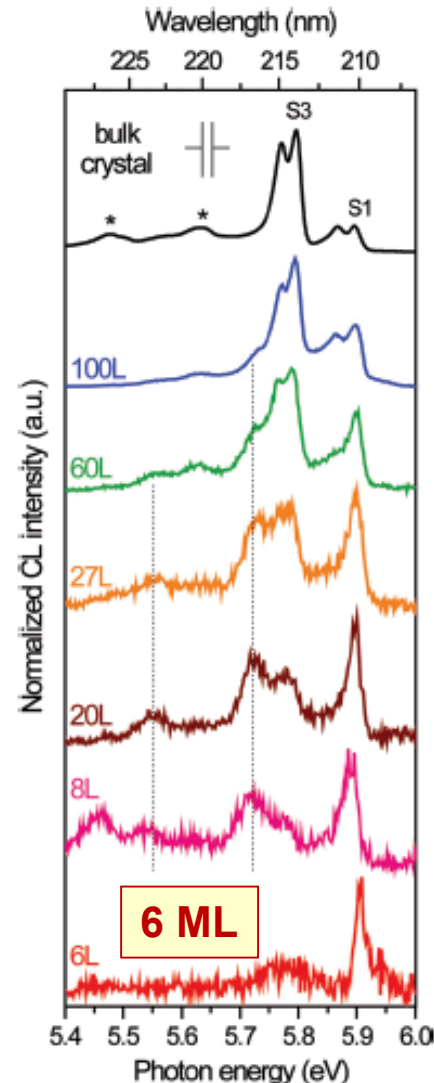


5.46 eV CL

Pierret, PRB (2014)

Loss of higher energy, free-exciton related features with exfoliation

Low Temp CL: Exfoliated hBN Flakes

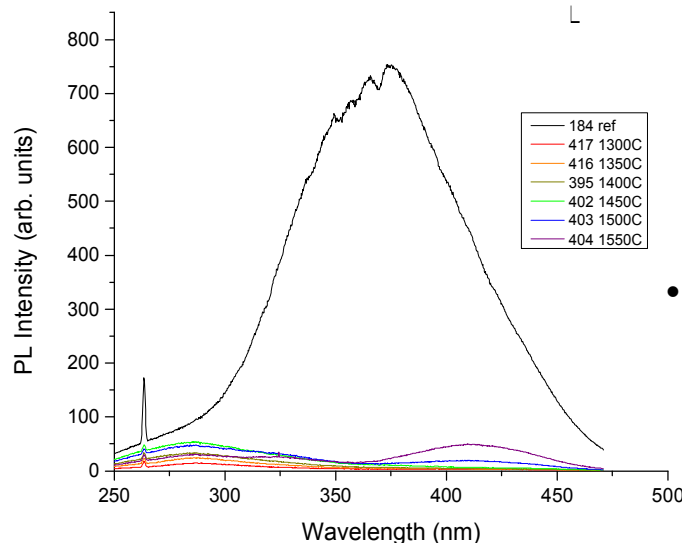
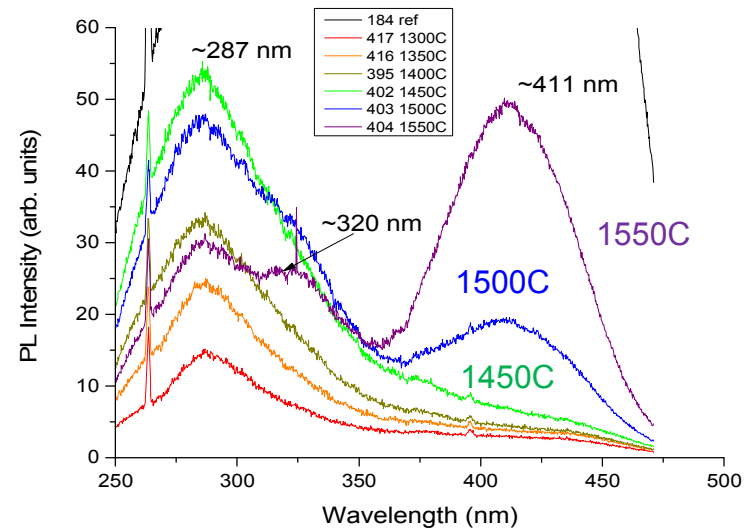
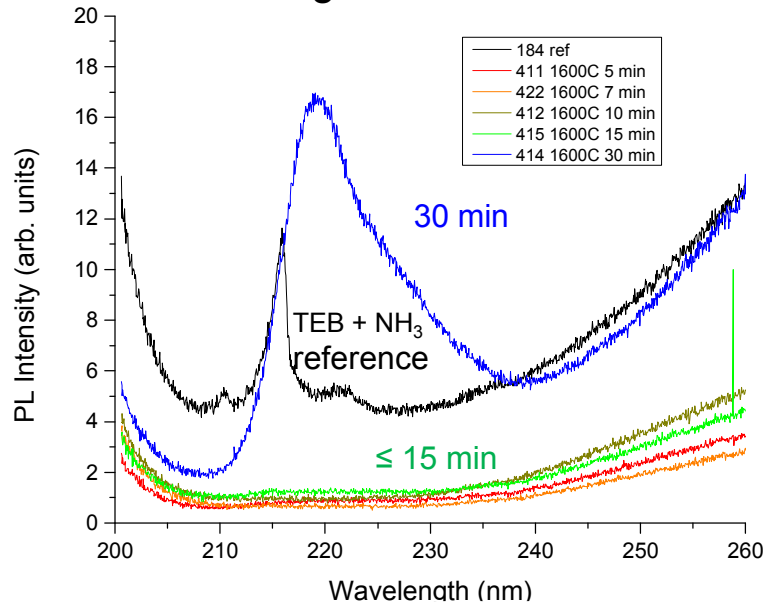


Improved Exfoliation: excitonic evolution down to 6 ML

→ Explore epitaxial growth approaches

PL variations observed for hBN using Borazine

- Longer growth times/ thicker films needed for near band-edge emission
- Deep level peaks dependent on growth temp
- Origin may be from defects in sapphire



- Nitrided sapphire deep-level peak is avoided with borazine at all growth temperatures

Nucleation Theory

- In depth study of nucleation of hBN on sapphire
- Not possible with commonly-used TEB and NH_3 sources, substrate degradation

Nucleation Theory

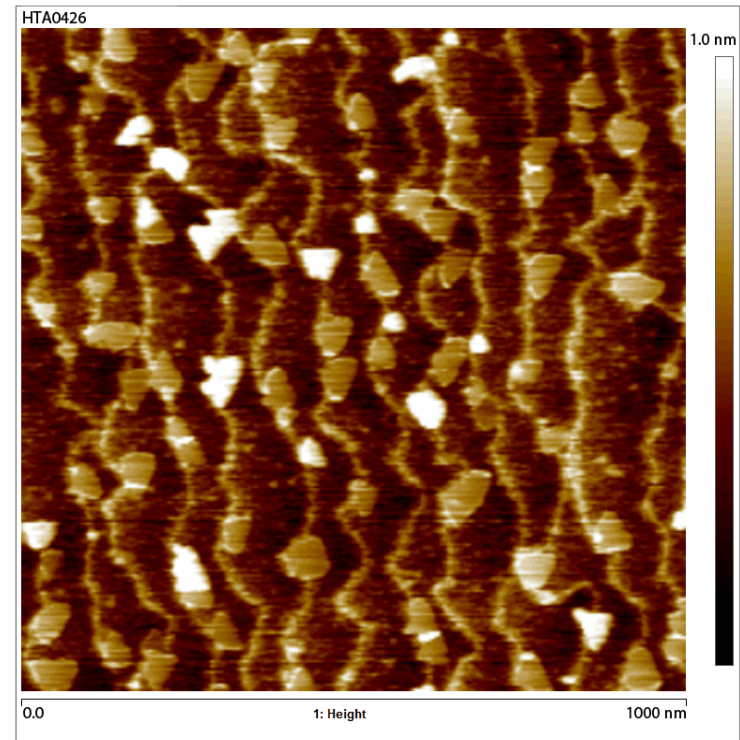
- Control of nucleation is critical for heteroepitaxy
- Classical Nucleation:

$$N = C e^{-\Delta G/kT}$$

Nuclei Density Adatom Density Temperature

- Would expect:
 - Higher temperature = Less nuclei
 - More precursor = More nuclei

AFM

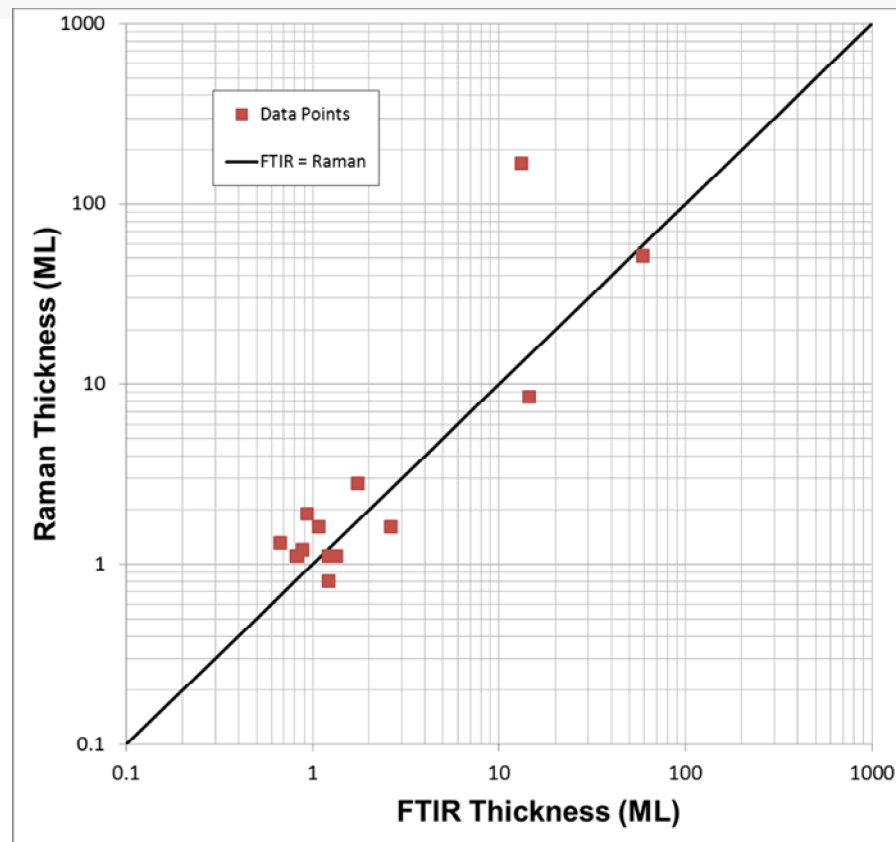


BN nuclei on sapphire
Deposition at 1450 °C

Comparison of Two Techniques

Sample	FTIR Thickness (ML)	Raman Thickness (ML)
427	0.83	1.1
444	0.85	0
445	0.89	1.2
468	59.39	51
473	13.22	168*
474	14.55	8.4
476	1.22	1.1
478	2.64	1.6
479	0.94	1.9
480	0.55	0
481	0.82	1.1
482	0.67	1.3
485	1.34	1.1
488	1.22	0.8
489	1.76	2.8
490	1.08	1.6

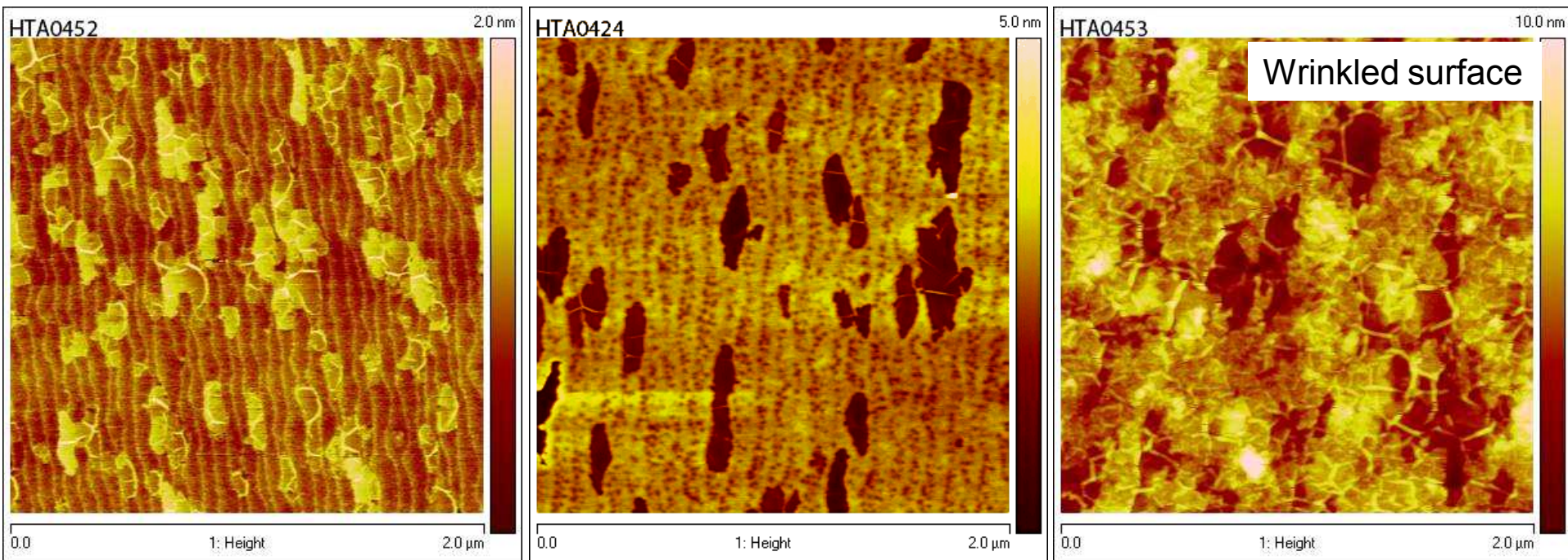
* Anomalous data point



- No systematic over or underestimation between approaches

Morphology

Atomic Force Microscope images: 3 characteristic morphologies



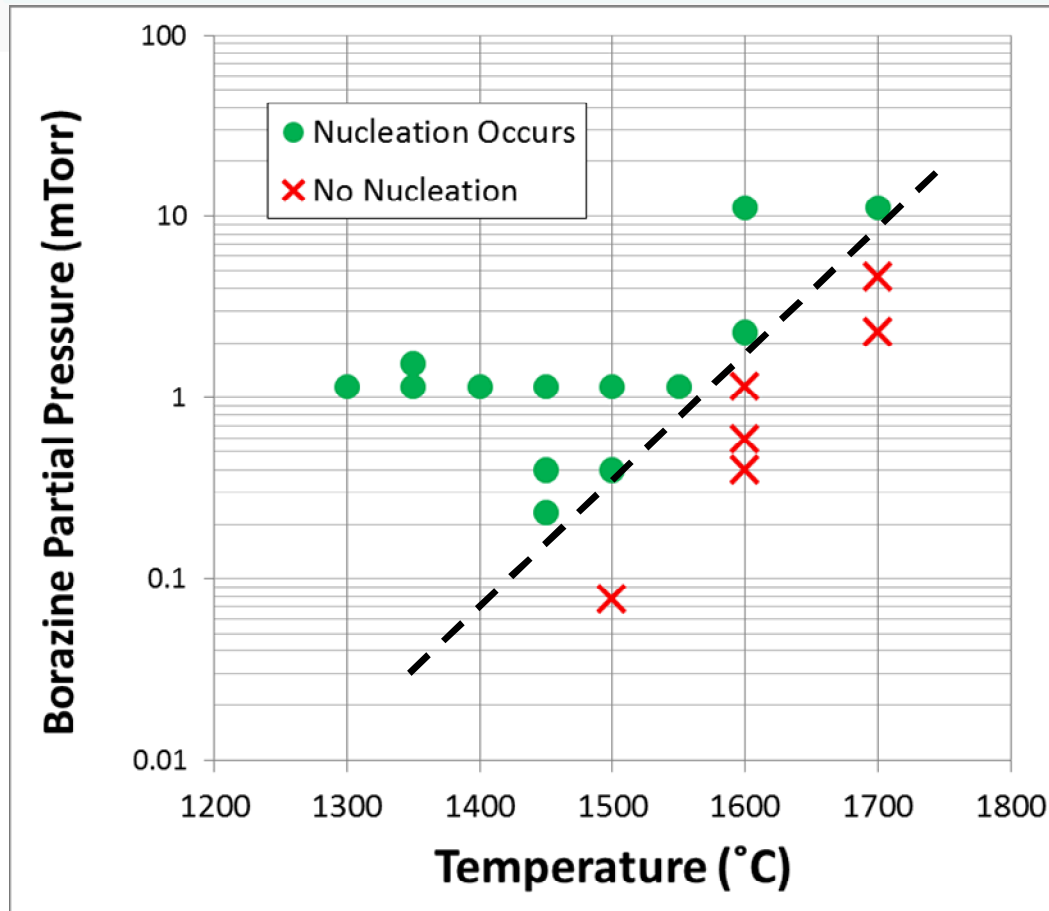
1 monolayer or less
RMS roughness ~ 0.2 nm

1 to 3 monolayers
RMS roughness ~ 0.5 nm

3 monolayers or more
RMS roughness > 1 nm

- Morphology dependent only on film thickness
- Growth temperature and borazine flux impact only nucleation

Experimental Nucleation Studies



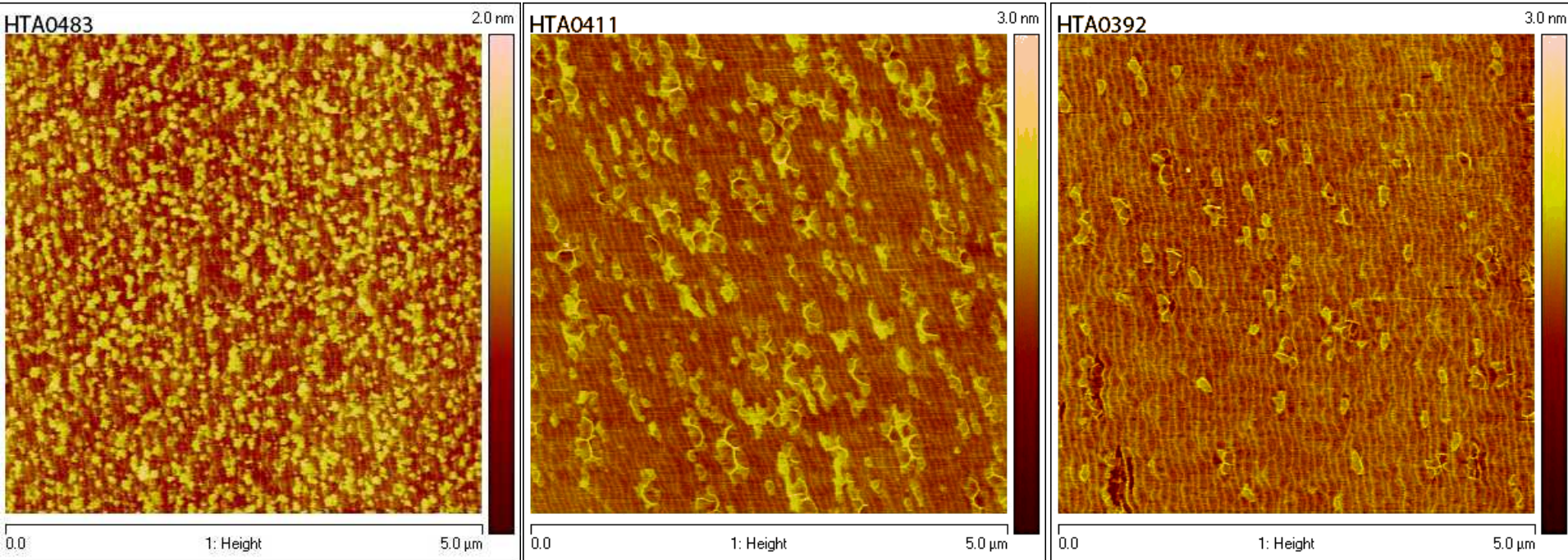
- Critical borazine partial pressure for nucleation to occur
- Strong function of growth temperature

Nucleation with Flux

2 min at 1.5 $\mu\text{mol/min}$

5 min at 0.75 $\mu\text{mol/min}$

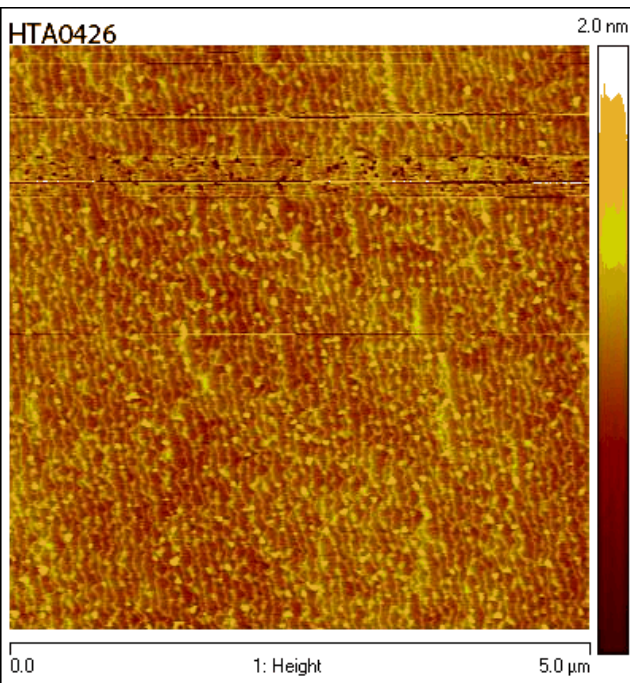
5 min at 0.37 $\mu\text{mol/min}$ +
15 min at 0.13 $\mu\text{mol/min}$



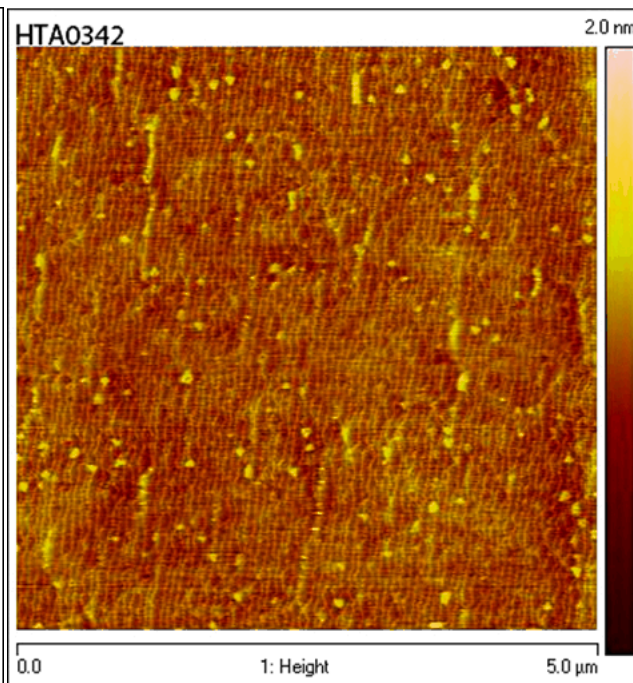
- Fixed temperature of 1600 $^{\circ}\text{C}$
- Nuclei density decreases with decreasing flux
 - Consistent with classical nucleation theory

Nucleation with Temperature

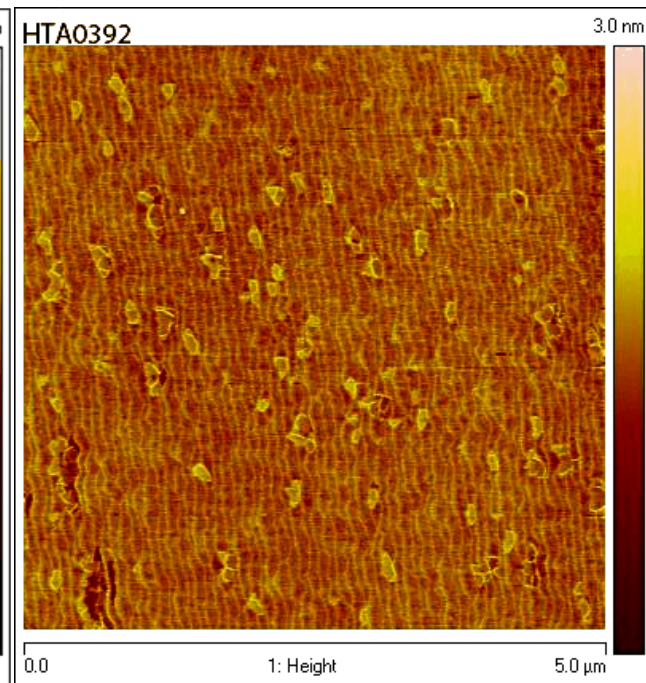
1450 °C



1500 °C



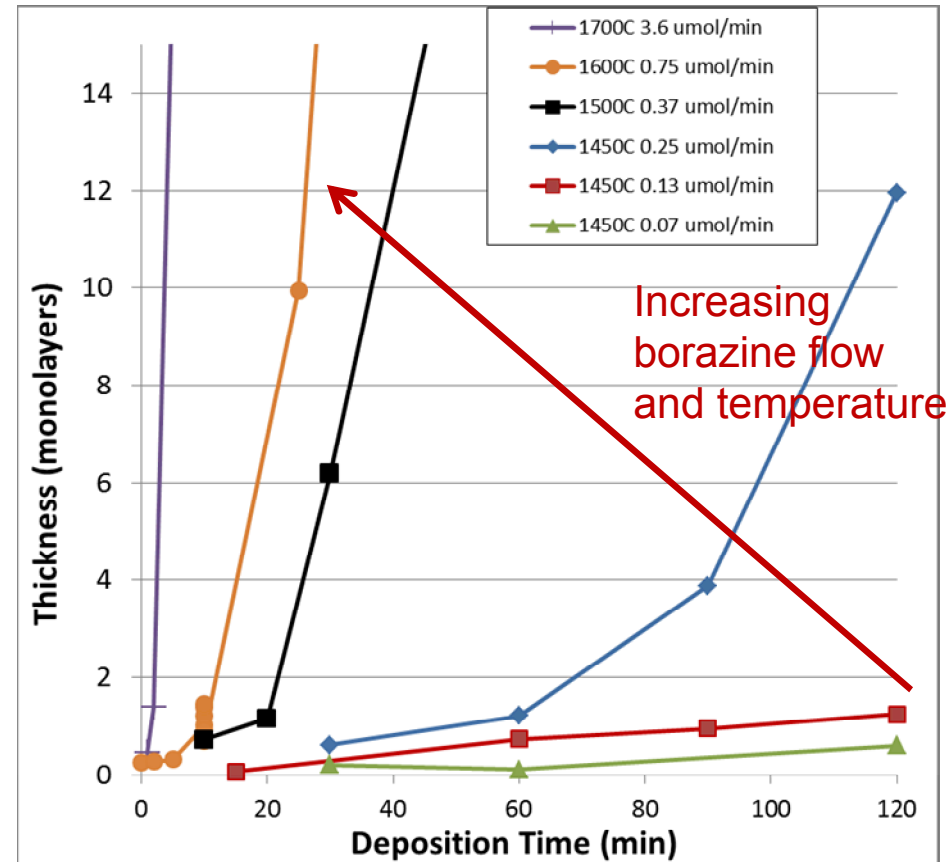
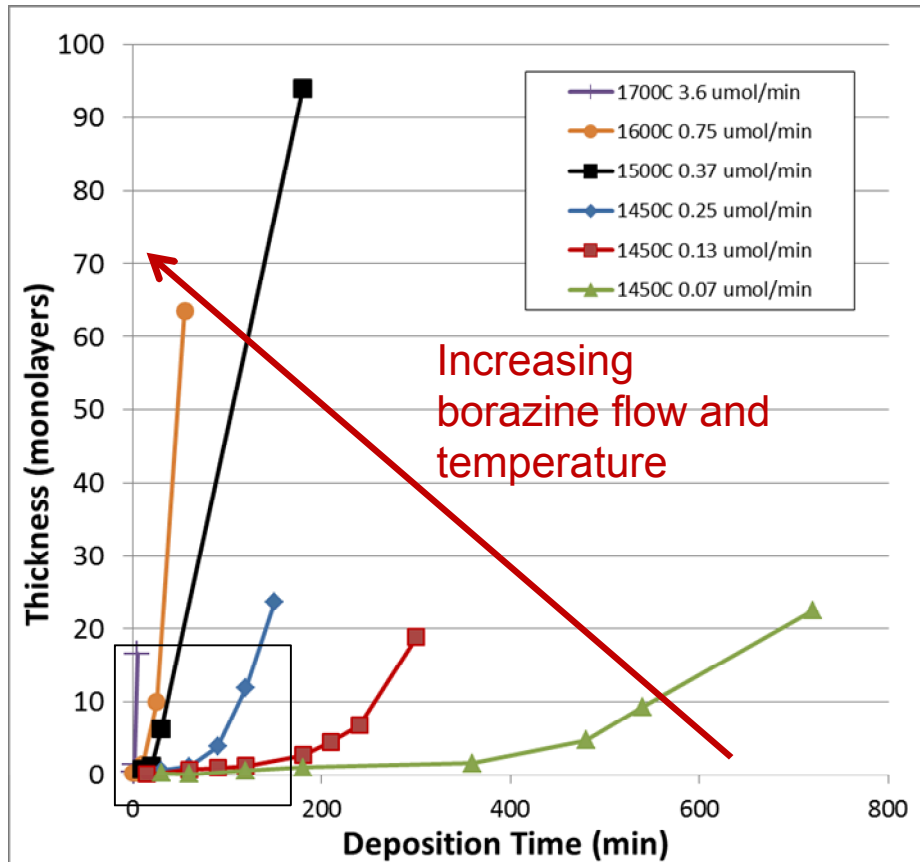
1600 °C



- **Fixed flux and dosage of borazine**
 - 5 min at 0.37 μmol/min + 15 min at 0.13 μmol/min
- **Nuclei density decreases with increasing temperature**
 - Consistent with classical nucleation theory

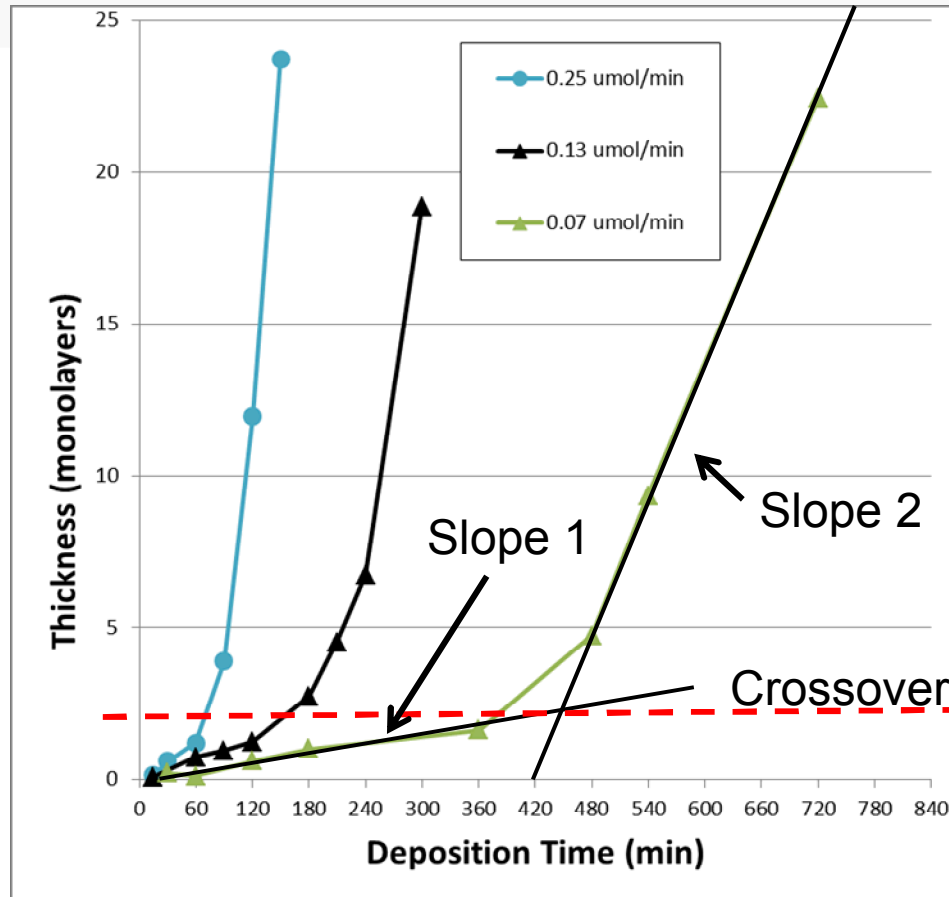
Film Deposition with Borazine

Expanded View



- Deposition rate is not constant with time

Film Deposition with Borazine



- Change in deposition behavior consistently seen at ~2 monolayers

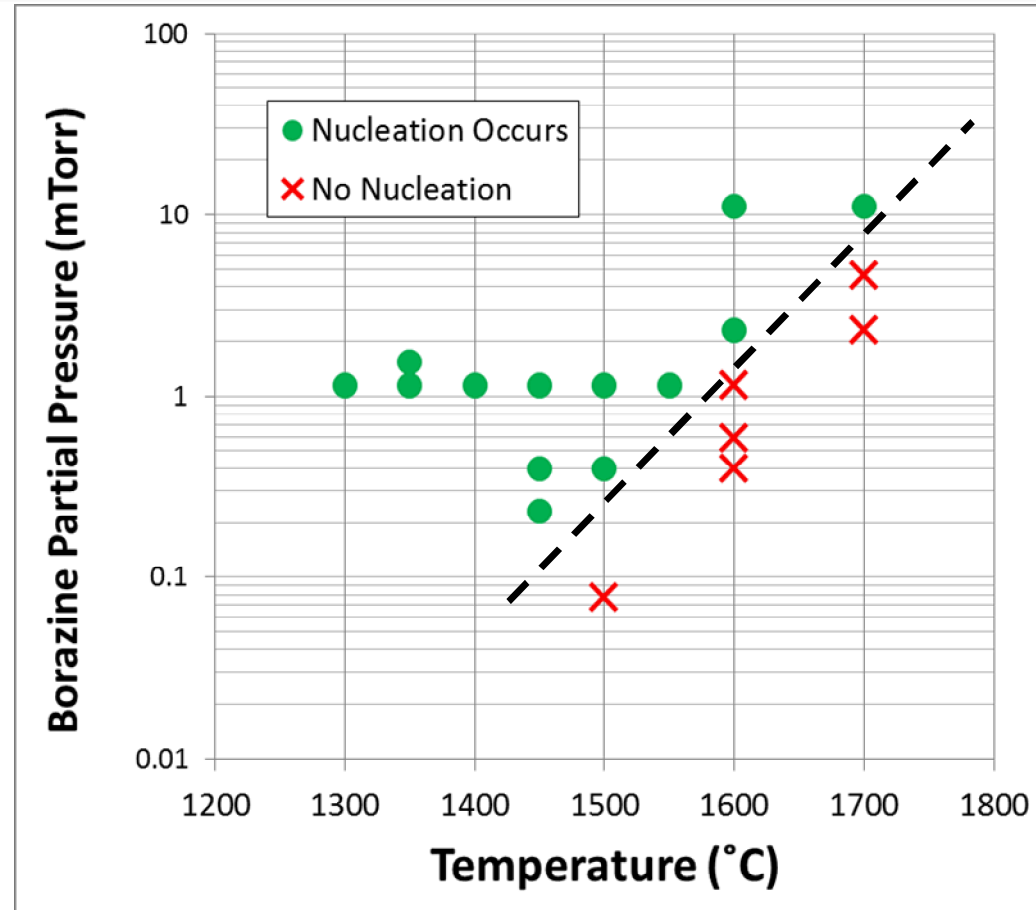
Separating Nucleation and Growth

Nucleation

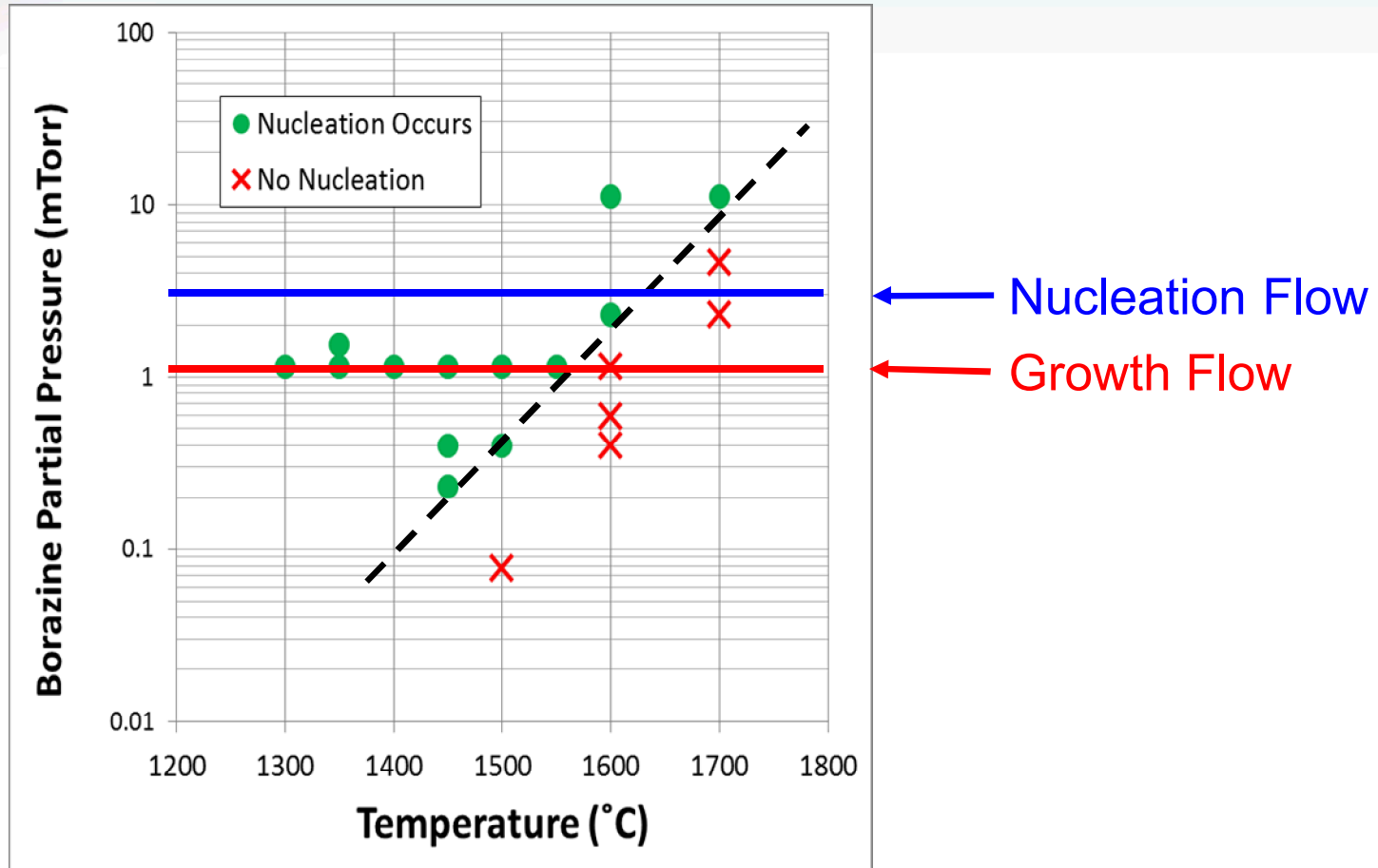
- Threshold determined by supersaturation
- Must overcome an energetic barrier to nucleate

Deposition

- Net mass flux to growth surface must be positive
- Just need a higher input partial pressure than equilibrium partial pressure



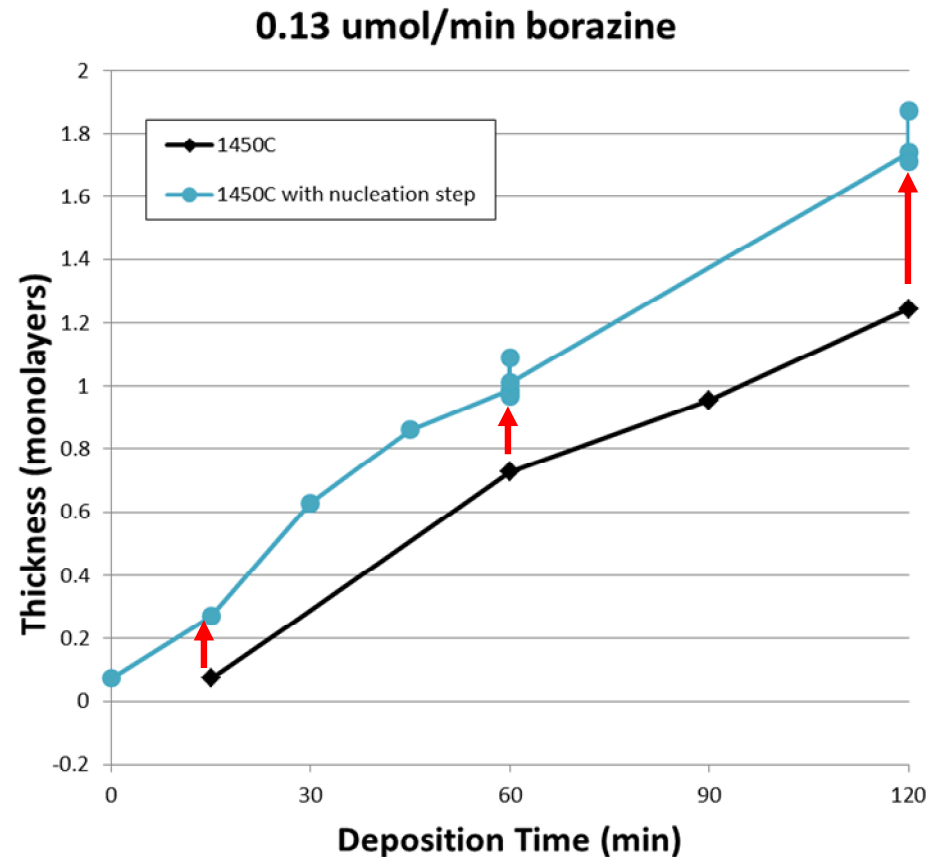
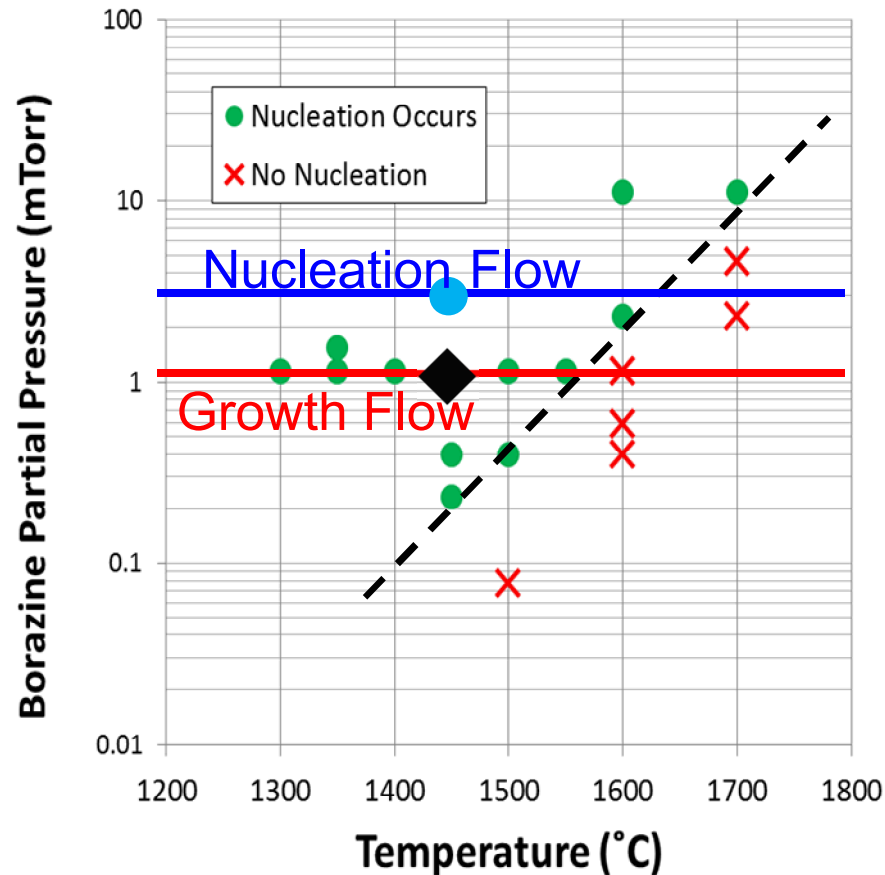
Separating Nucleation and Growth



- “Nucleation step” is 5 minutes at 0.37 $\mu\text{mol/min}$ borazine
- Growth at 0.13 $\mu\text{mol/min}$ borazine

Separating Nucleation and Growth

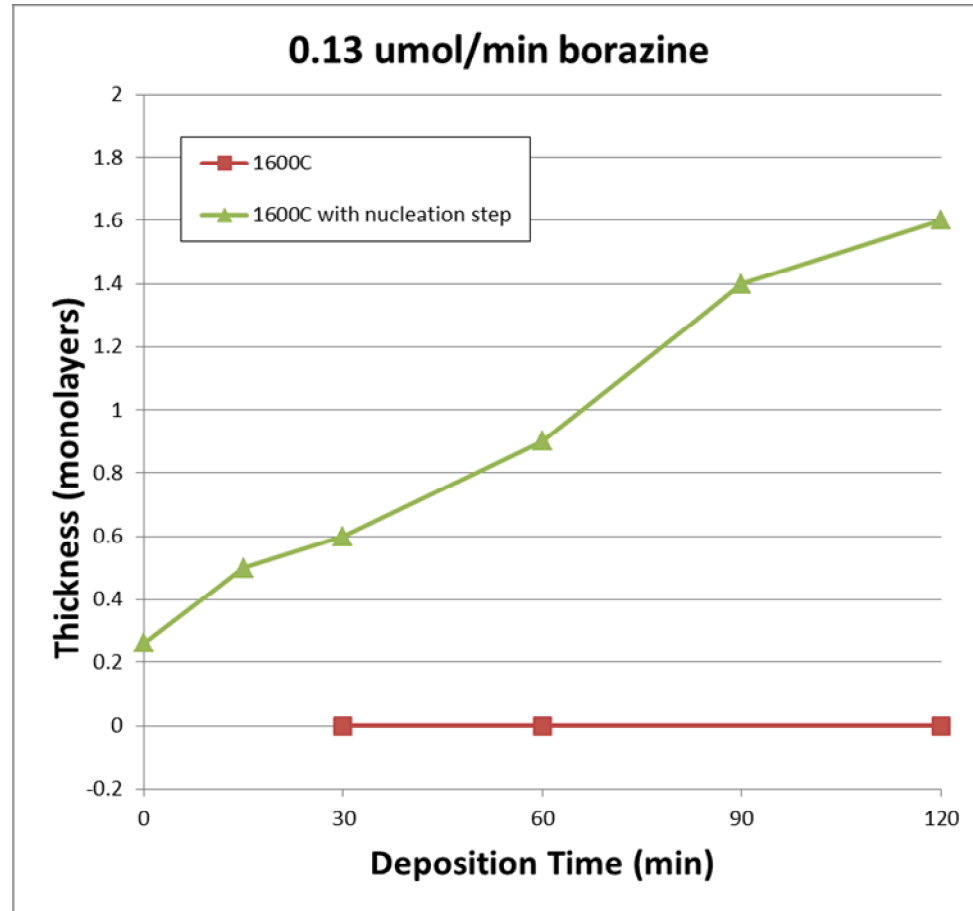
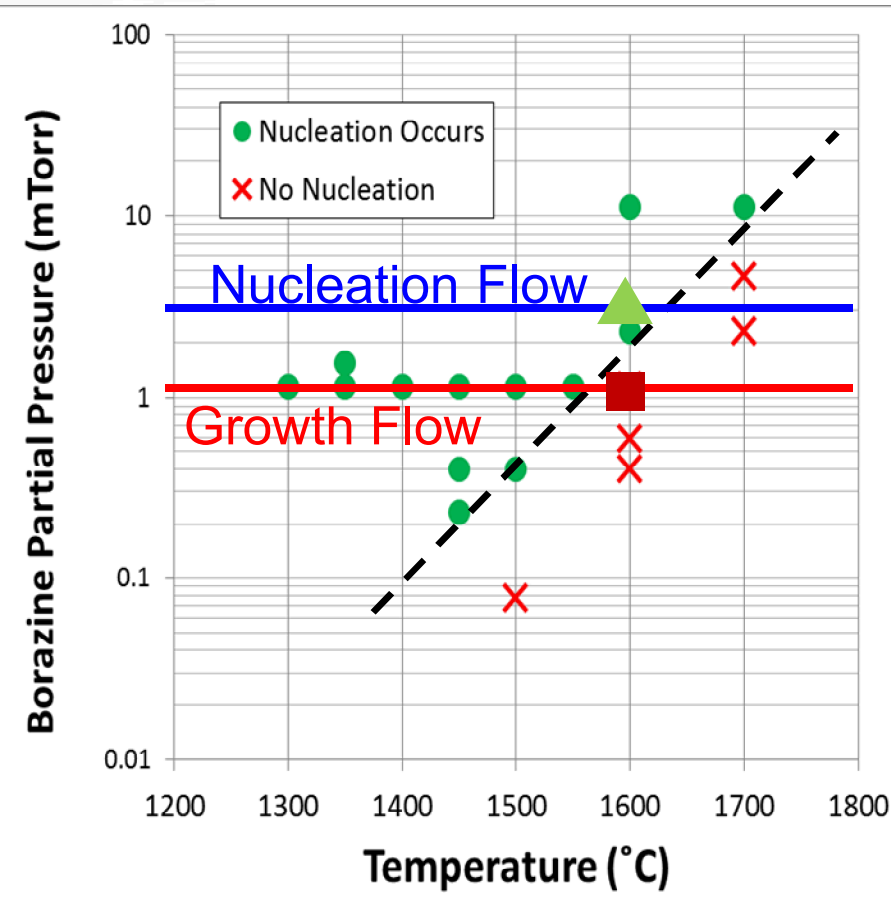
Case 1: $T_g = 1450\text{C}$



- “Nucleation step” is 5 minutes at $0.37\text{ }\mu\text{mol/min}$ borazine
- Growth at $0.13\text{ }\mu\text{mol/min}$ borazine

Separating Nucleation and Growth

Case 2: $T_g = 1600\text{C}$



- “Nucleation step” is 5 minutes at $0.37 \mu\text{mol/min}$ borazine
- Growth at $0.13 \mu\text{mol/min}$ borazine

→ Nucleation step is critical for higher growth temperatures